

REINHOLD ENVIRONMENTAL Ltd.



2012 APC Round Table & Expo Presentation

July 16-17, 2012, in Baltimore, MD / Hosted by Duke Energy, Entergy,
FirstEnergy, Southern Company & TVA

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Challenges in Capturing Very Low to Very High Resistivity Dust

PCUG/Round Table
Reinhold Environmental

Per Ranstad
Jörgen Linner
Anders Karlsson

Baltimore, July 17th, 2012

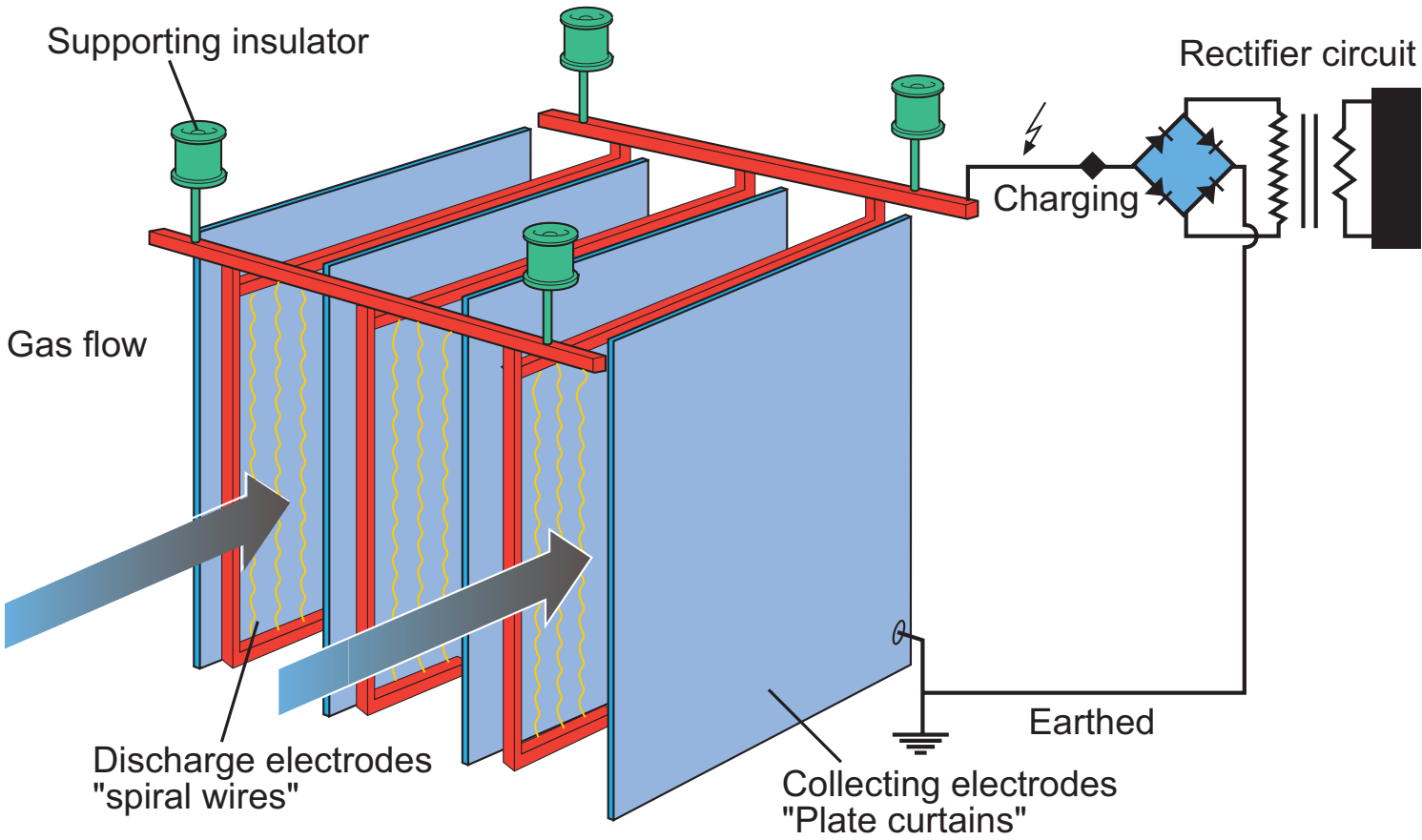
POWER

ALSTOM

- *Introduction*
- *Holding forces, variations in time*
- *High voltage measurements*
- *Resistivity control by means of*
Power Control Rapping
- *Summary*

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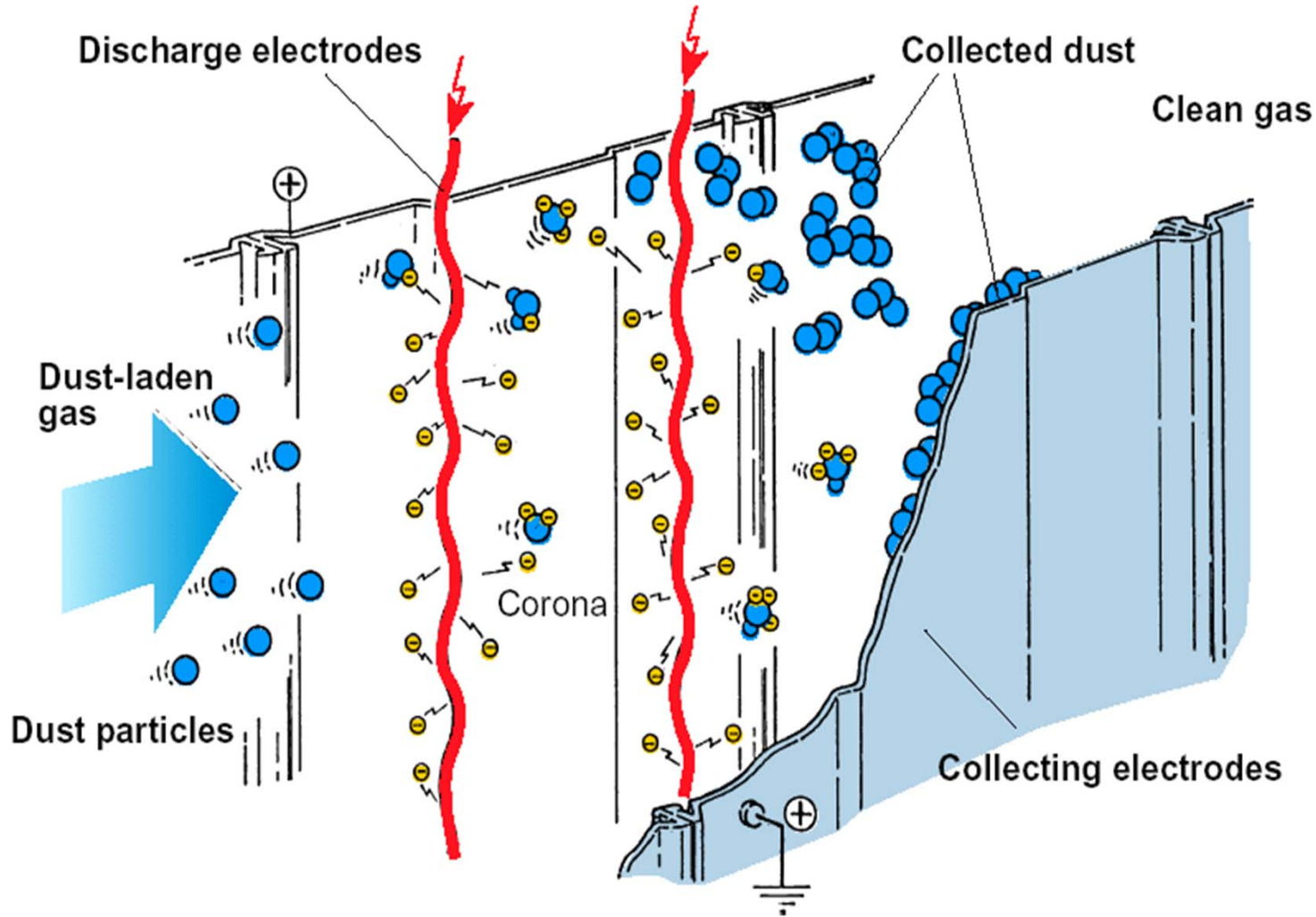
Principal design of Electrostatic Precipitator



PCUG/Round Table - July 17th 2012, Baltimore

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ESP dust collection



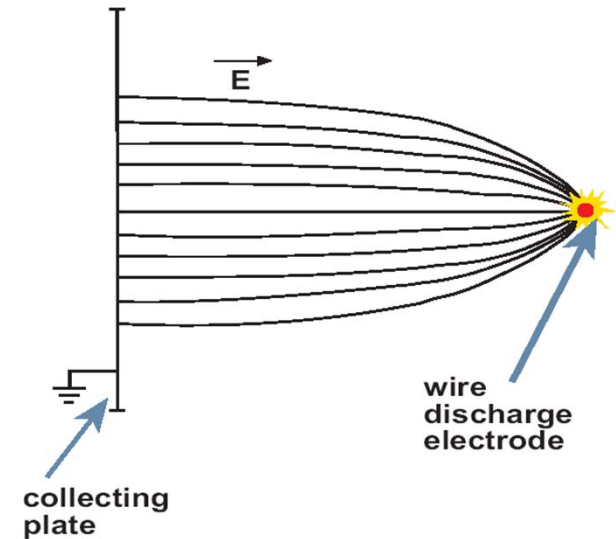
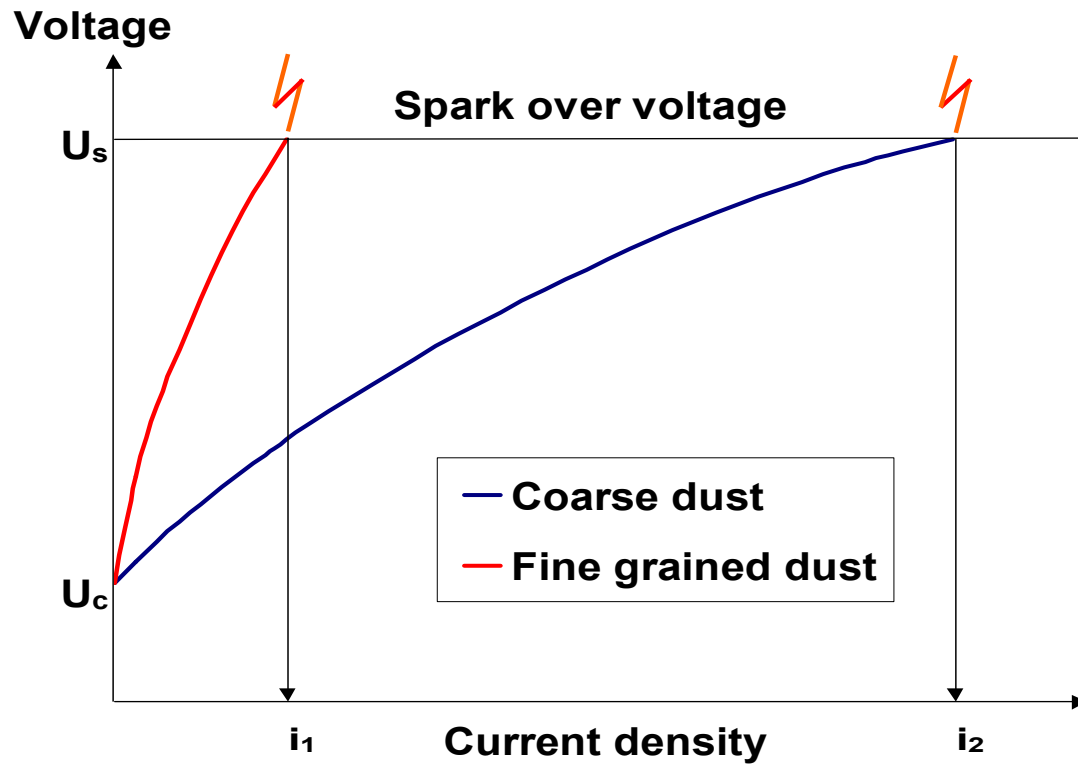
2.2

- Corona quenching
 - *Particle size distribution, 'Fine dust'*
 - *Reduced E-field at the emitting electrode*
=>*Less Corona current*

- Back Corona
 - High resistivity dust
 - High E-field in the dust layer, spark-over
=>Injection of positive charges into the gas

- Reentrainment
 - Low resistivity dust
 - Low E-field in the dust layer
=>Reduced holding forces in the dust layer

Poor Power Input



Fine grained dust increases the Space Charge Effect,
i.e. Corona Quenching

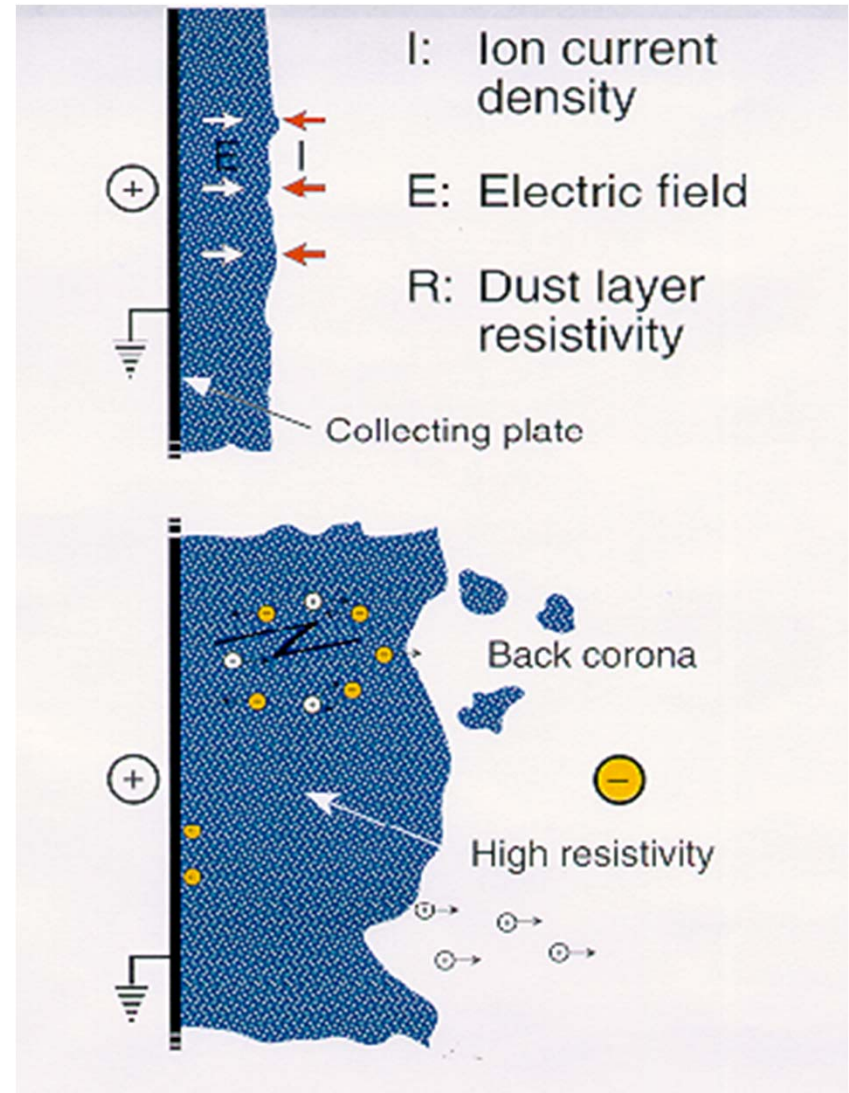
Back-Corona in ESP

$$E = j \rho$$

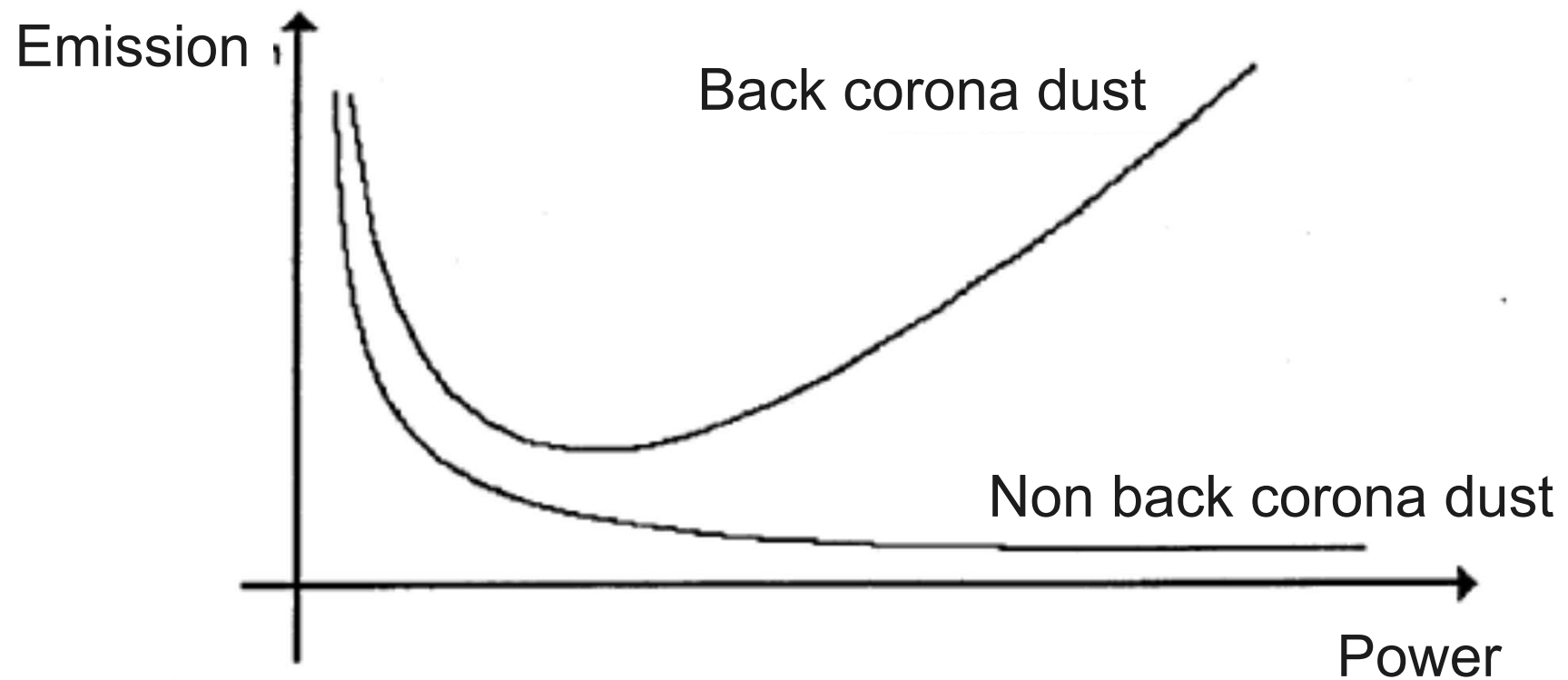
E Field strength, [V/m]

j Current density, [A/m²]

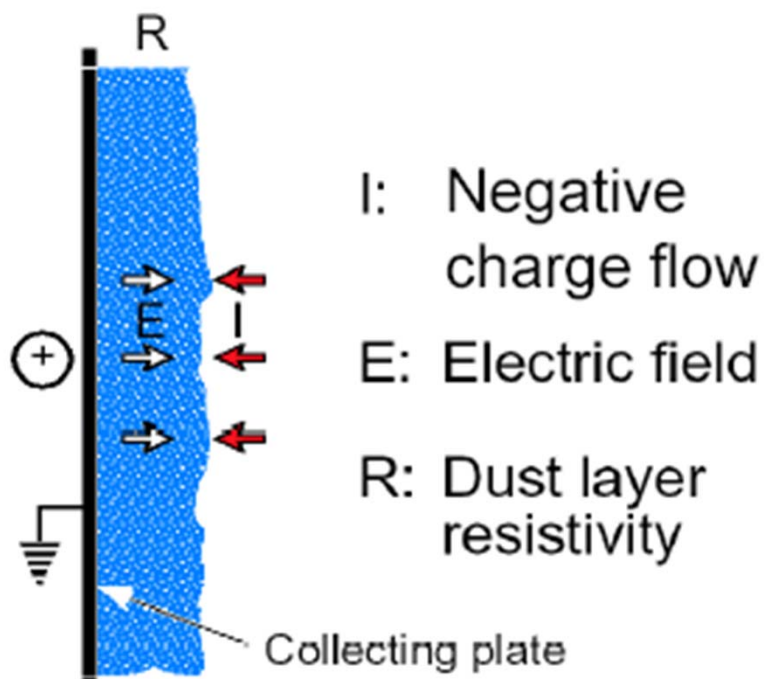
ρ Dust layer resistivity, [Ω m]



Dust emission vs. power consumption



Low resistivity dust, reentrainment



Tear off

Gas flow (drag)

Gravity

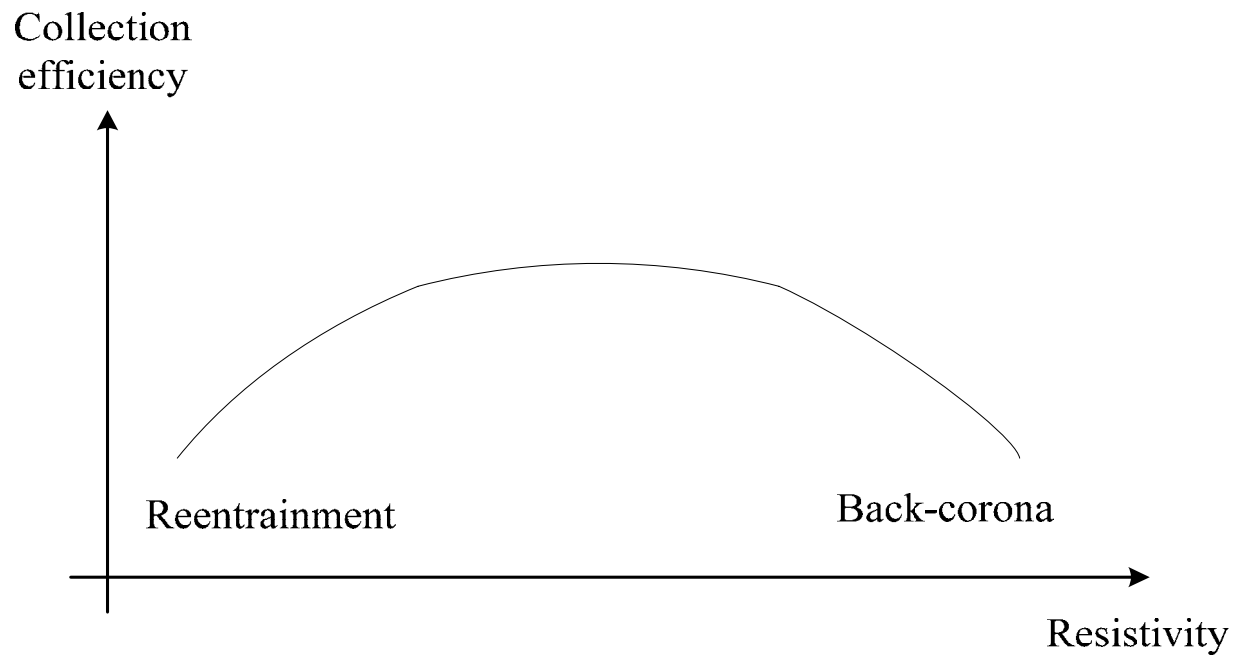
Holding

Electrostatic forces

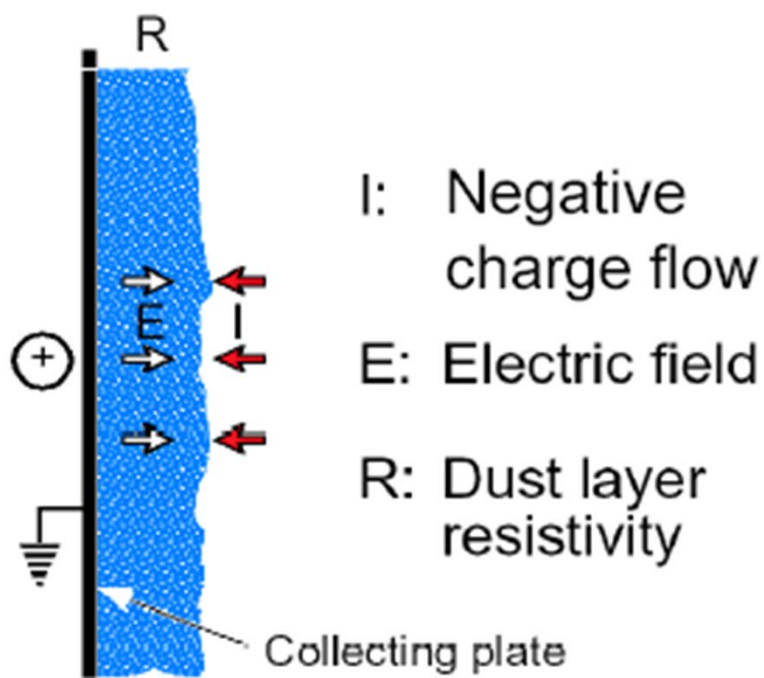
Chemical (cohesion)

Reentrainment related to low resistivity depends on the relation between dust layer electrostatics and gas flow close to the collecting electrode.

Dust emission vs. resistivity



Dust layer, resistivity



Classification 1

<i>Conductive</i>	$10^4-10^8 \Omega\text{cm}$
<i>Normal</i>	$10^8-10^{10} \Omega\text{cm}$
<i>Moderate</i>	$10^{10}-10^{11} \Omega\text{cm}$
<i>High</i>	$10^{11}-10^{13} \Omega\text{cm}$

[Parker et.al, Applied Electrostatic precipitation, 1997]

Classification 2

<i>Low</i>	$10^7-10^9 \Omega\text{cm}$
<i>Best perf.</i>	$10^9-10^{11} \Omega\text{cm}$
<i>High</i>	$10^{11}-10^{13} \Omega\text{cm}$

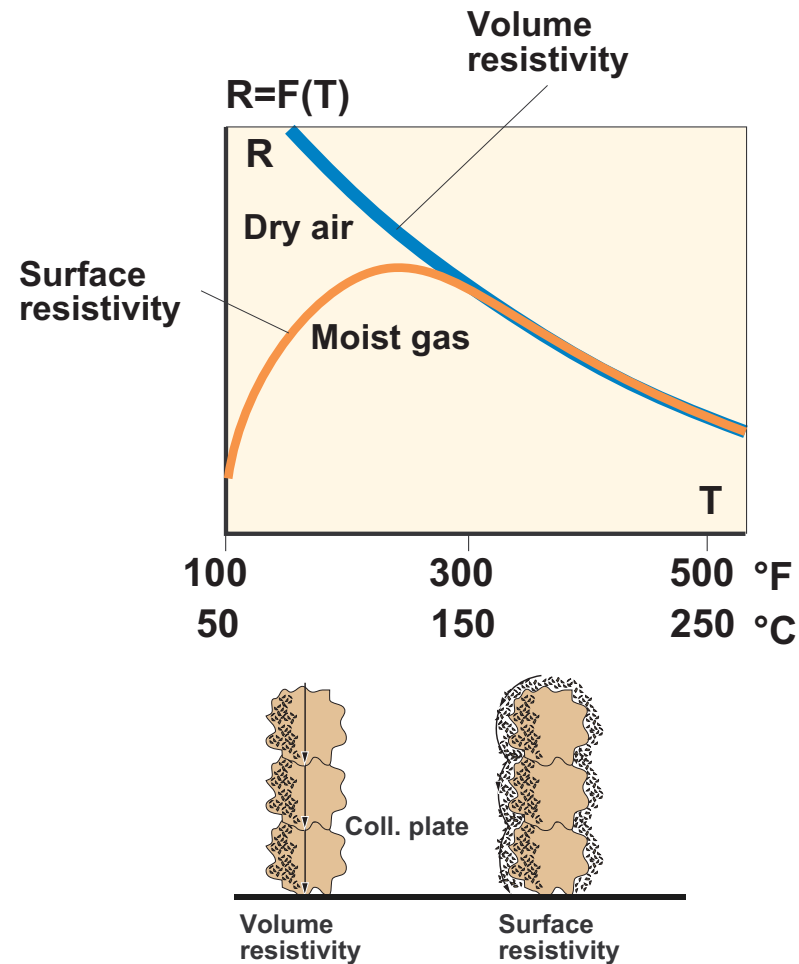
[Porle, Francis, Bradburn, ESPs for ind. Applications, 2005]

Classification 3

<i>High</i>	$>10^{10} \Omega\text{cm}$
-------------	----------------------------

[White, Industrial Electrostatic Precipitation, 1963]

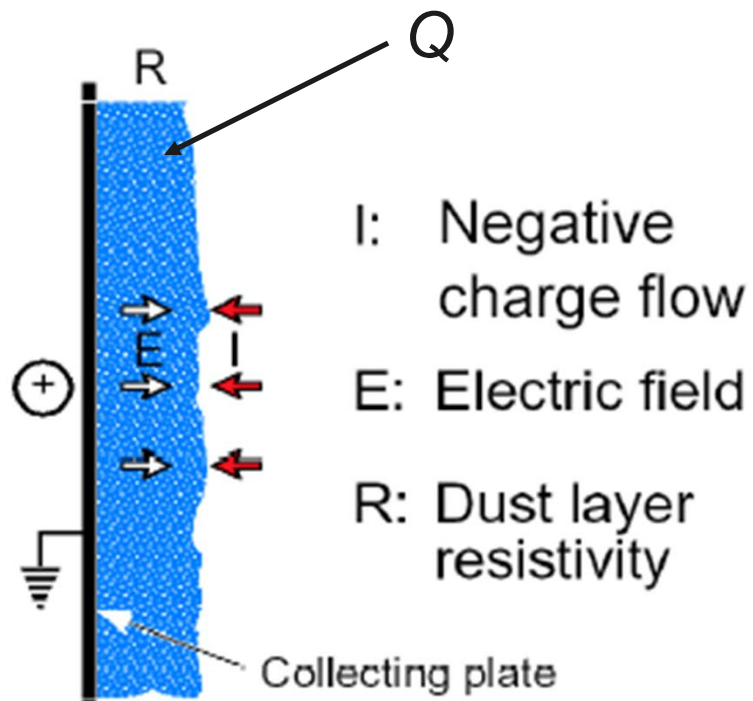
Dust resistivity versus moisture and temp.



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Dust layer, electrostatics



$$F = Q E$$

$$E = j \rho$$

$$\Rightarrow F = Q j \rho$$

F Force, [N]

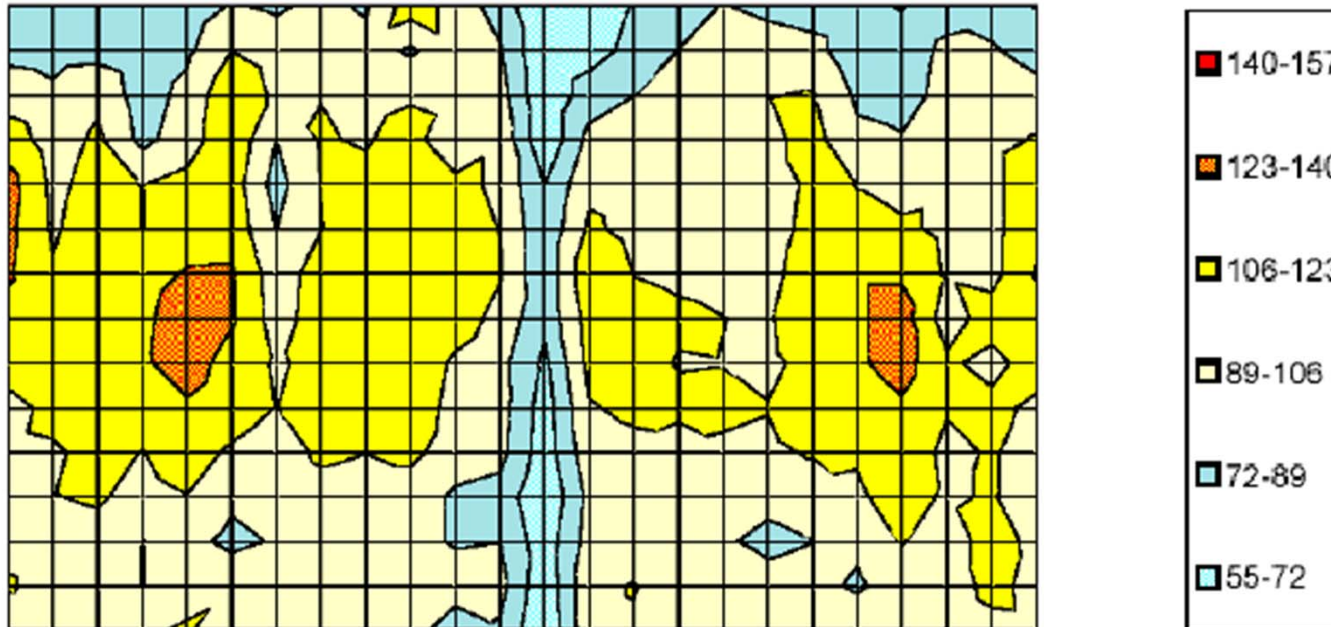
Q Charge, [C, (As)]

E Field strength, [V/m]

j Current density, [A/m²]

ρ Dust layer resistivity, [Ω m]

Gas flow distribution



Velocities in percentage of average

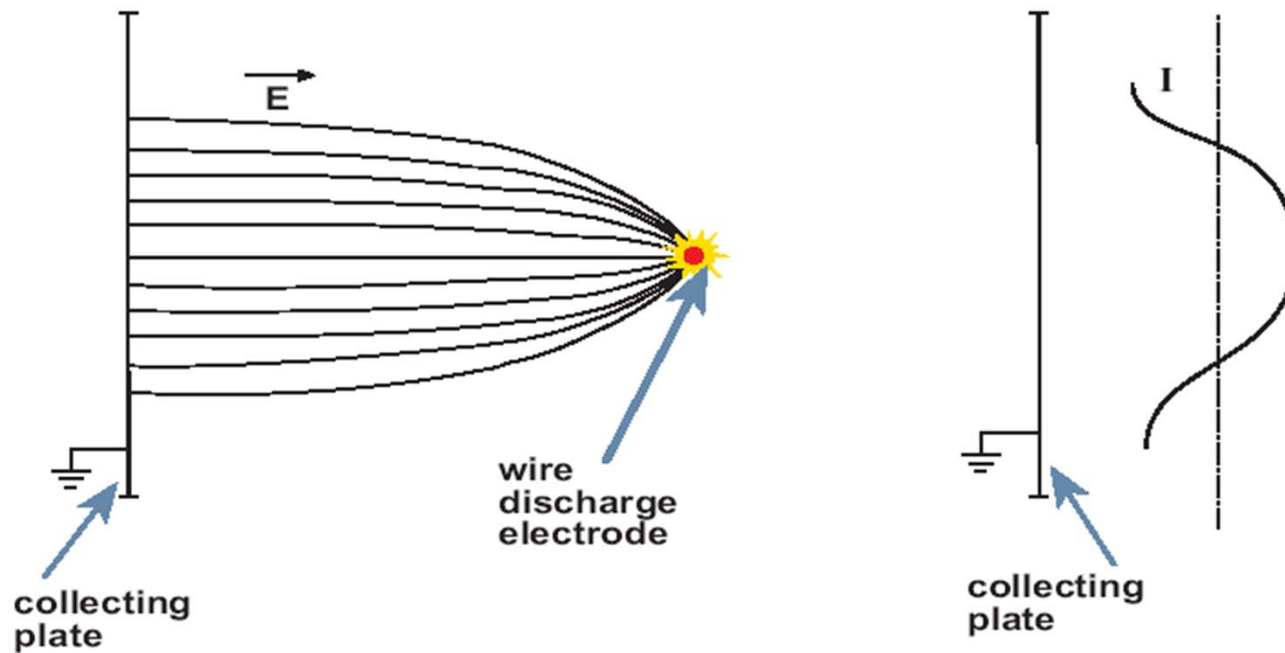
Measured after the first field

Gas flow distribution, means to minimize reentrainment

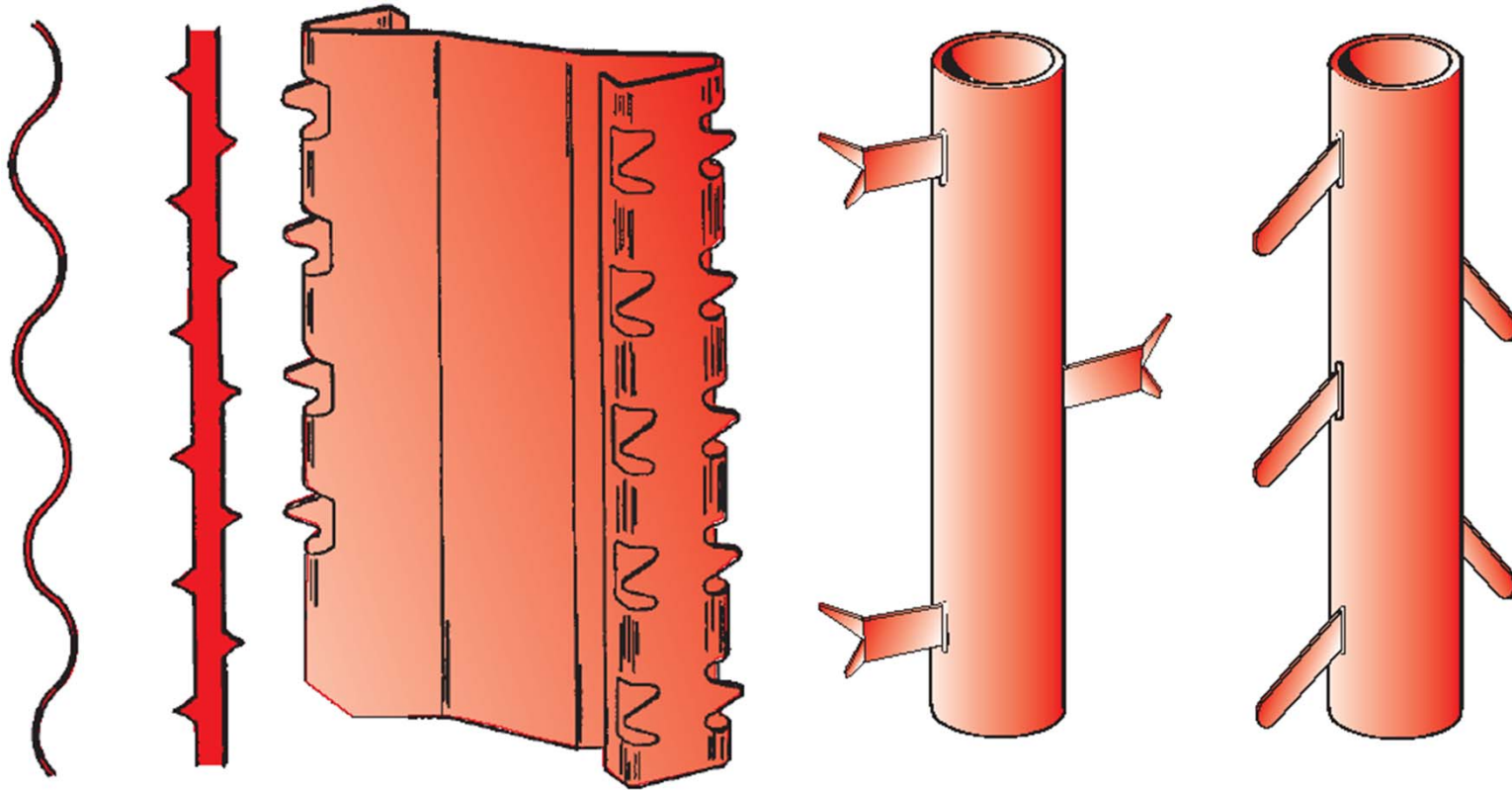


- Minimize high gas velocities
- Uniform flow distribution
- Avoid in-leakage

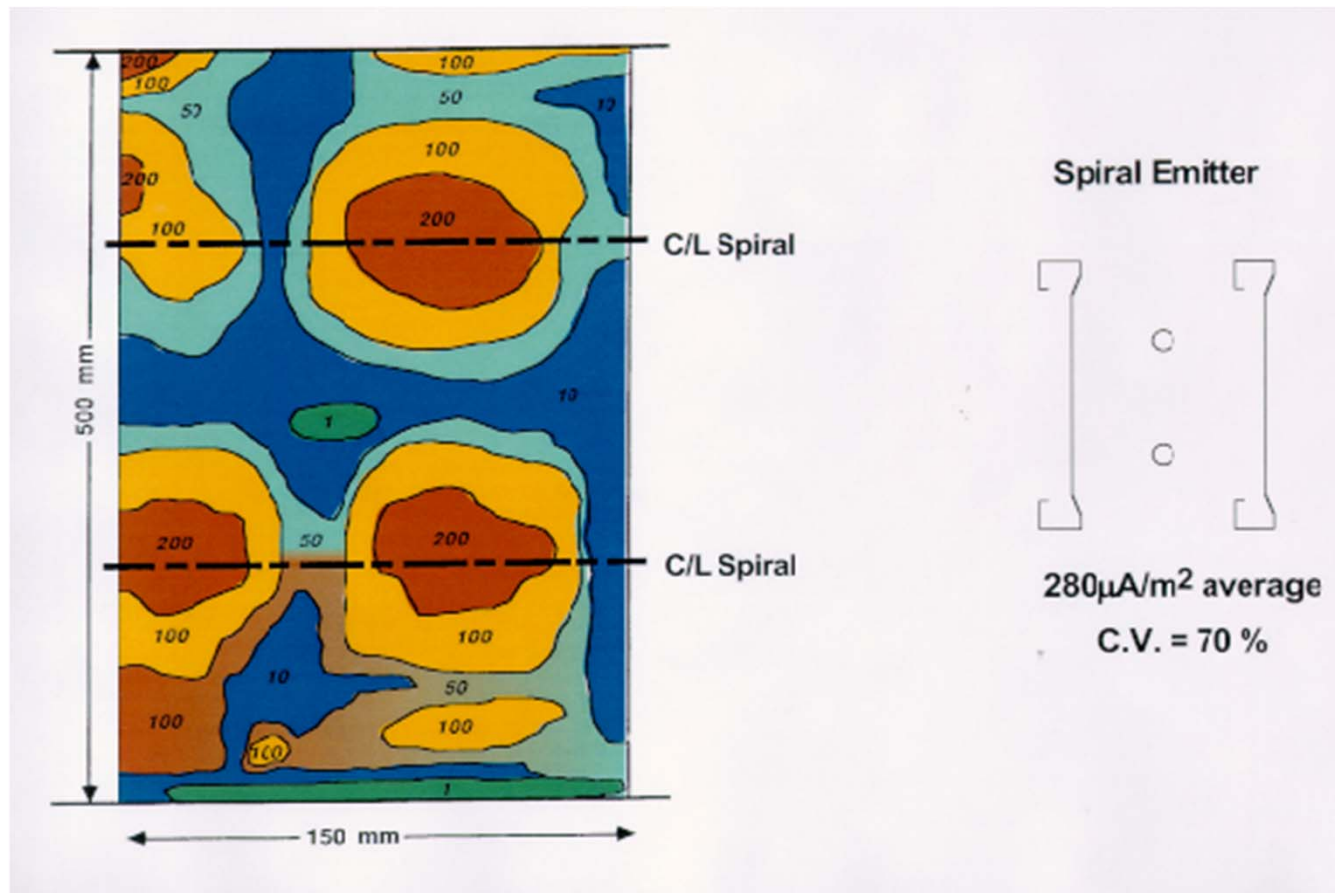
Current distribution, general



ESPs - discharge electrode

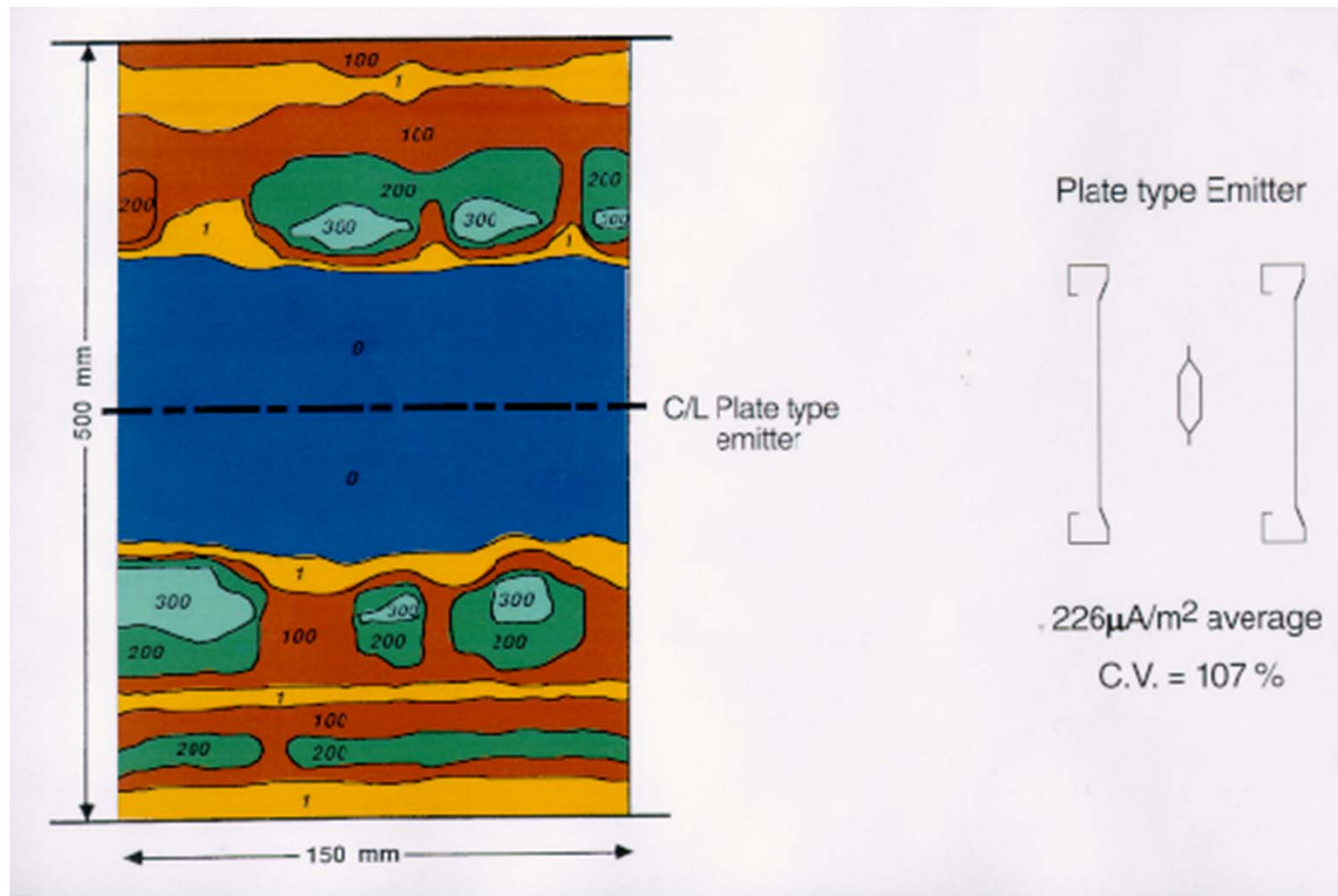


Current distribution on collecting plates



ESP - RDE discharge electrode, current distribution

Current distribution on the collecting plate

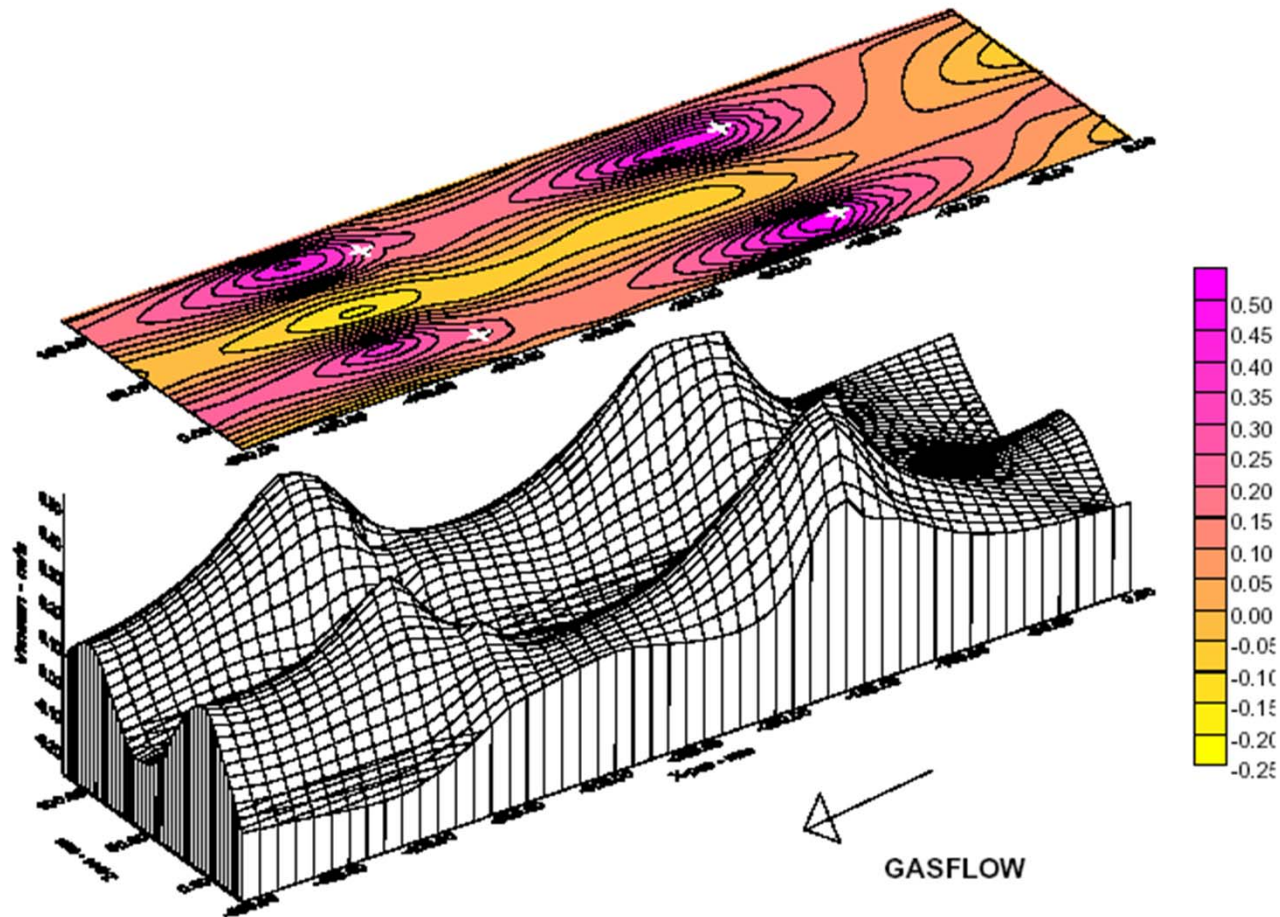


- Large areas with either high or zero current -

- Dust pattern similar to current distribution
- High CV-value in current distribution
- Poor utilisation of collecting plate
- Reentrainment



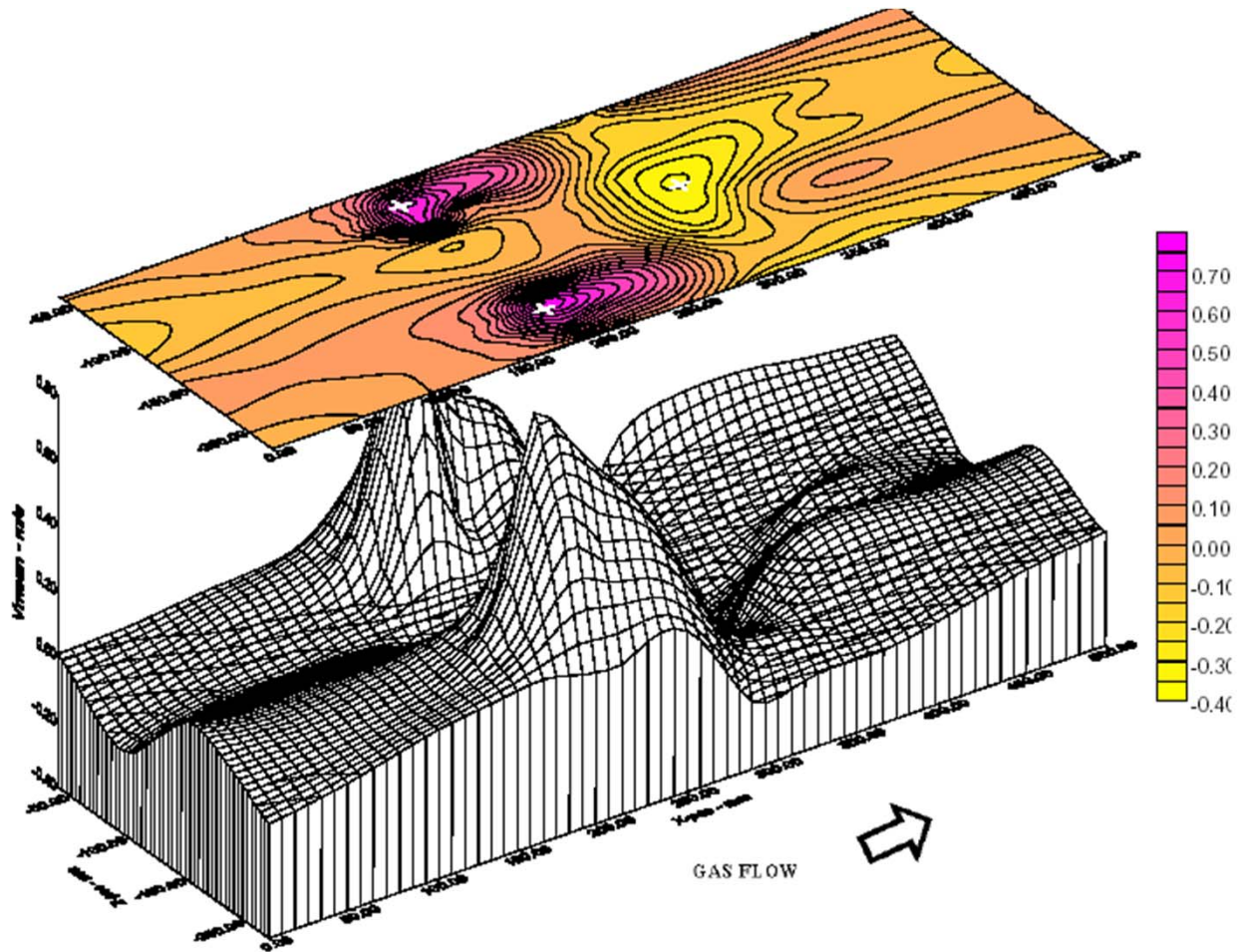
Ionic wind, spiral



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Ionic wind, RDE



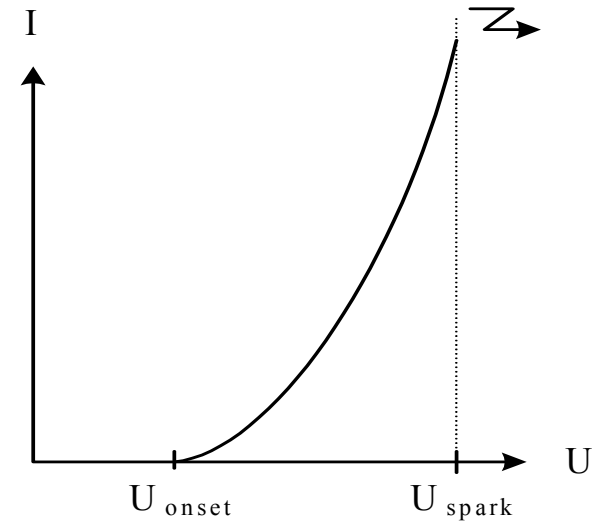
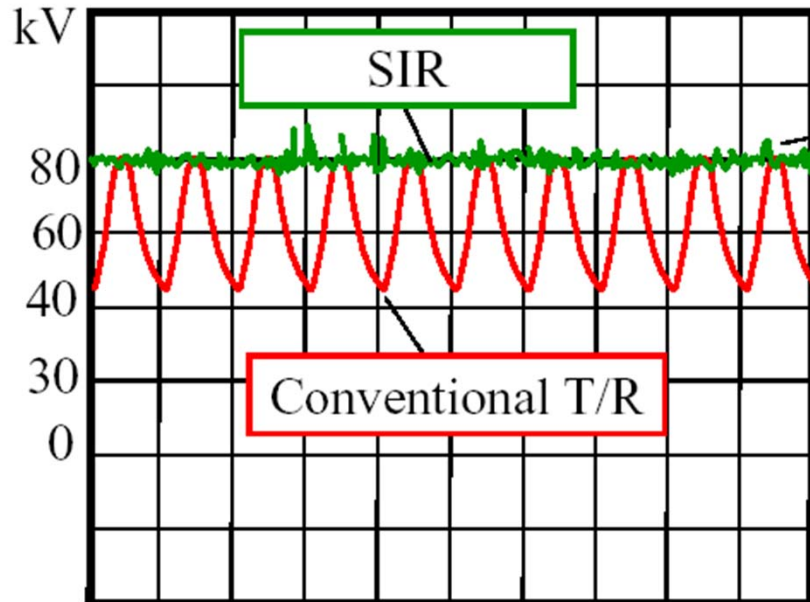
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- Influenced by emitting electrode design
- Non uniform current distribution gives:
 - Substantial areas of low current densities
 - Negative effect from the ionic wind, high current areas

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Voltage ripple vs reentrainment

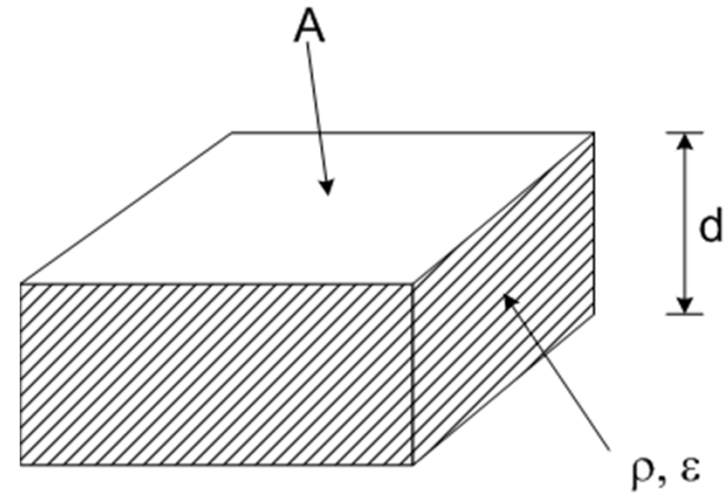
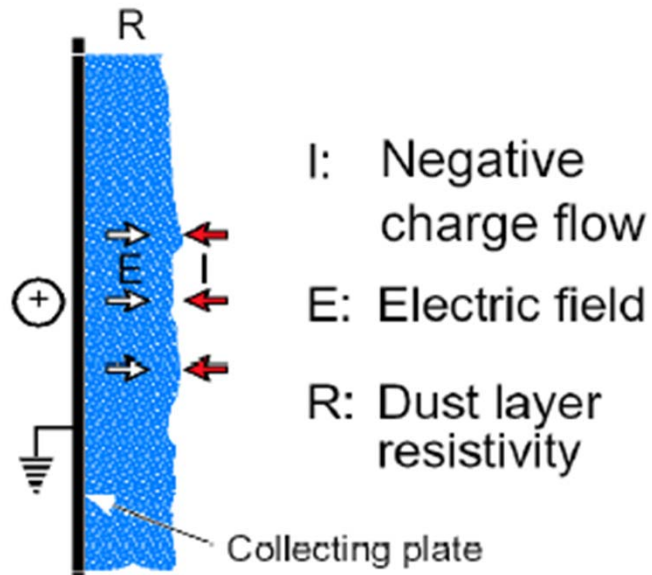


$$i_{Corona} = k \cdot (u - U_{Onset})^2$$

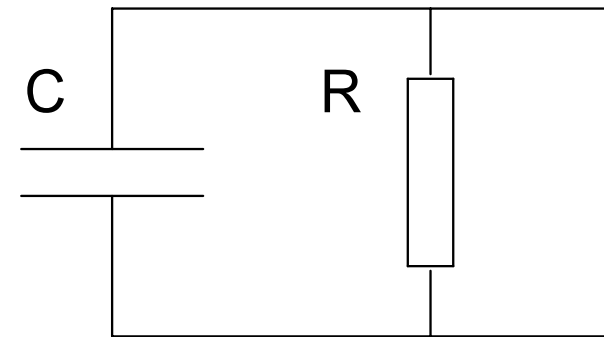
$$F = Q j \rho$$

$\Rightarrow F$ is very low at U_V

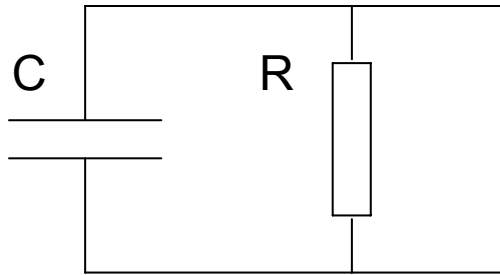
Dust layer, Time Constant



- τ Time constant, [s]
- A Area, [m²]
- d Distance, [m]
- ϵ Dielectric constant, [As/Vm]
- ρ Resistivity, [Ω m]

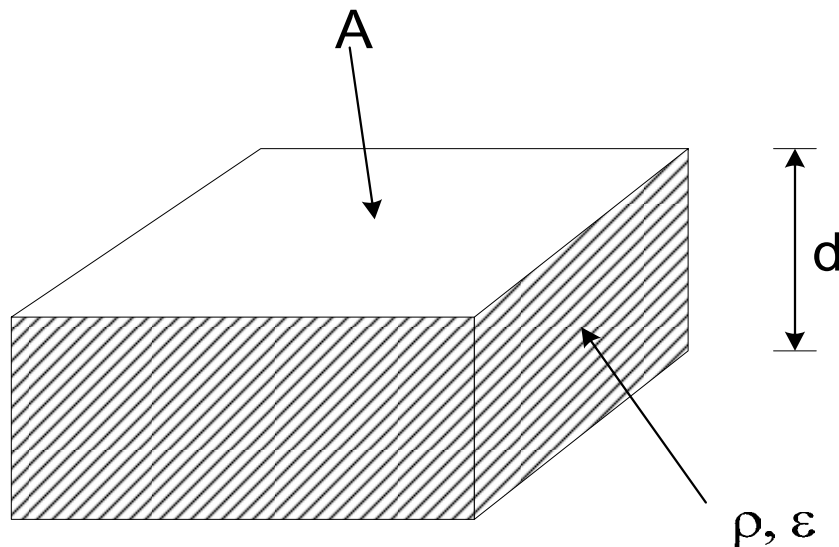


Estimation of dust layer time constant



$$C = \epsilon \frac{A}{d}$$

$$R = \rho \frac{d}{A}$$



$$\tau = R \cdot C = \rho \cdot \epsilon$$

Estimation of dust layer time constant



$$T=RC=\rho\varepsilon$$

$$\varepsilon=1 \cdot 8,85 \cdot 10^{-12} \text{ As/Vm} \approx 1 \cdot 10^{-11} \text{ As/Vm}$$

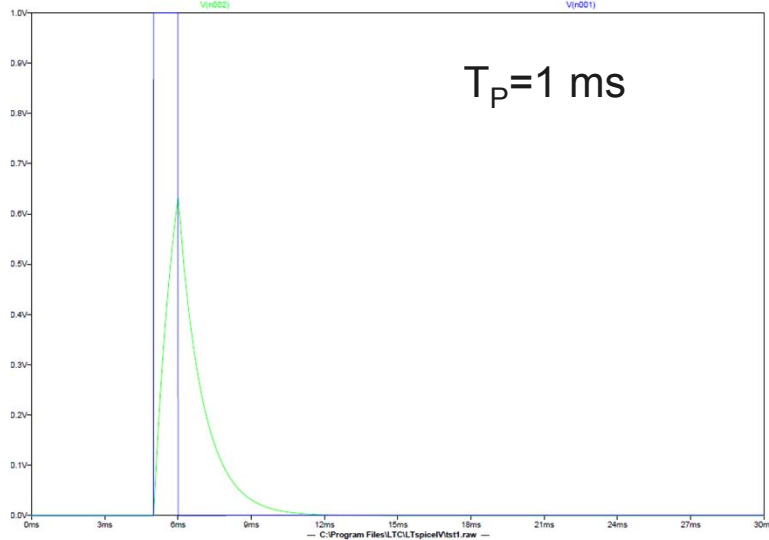
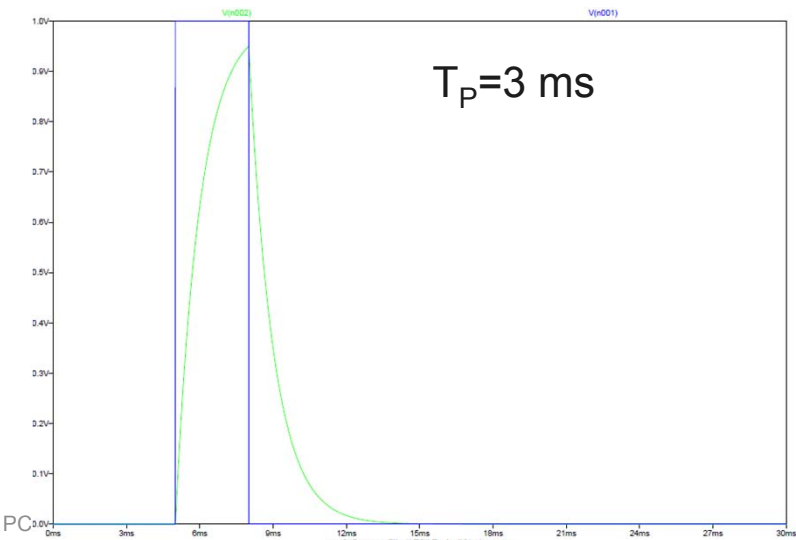
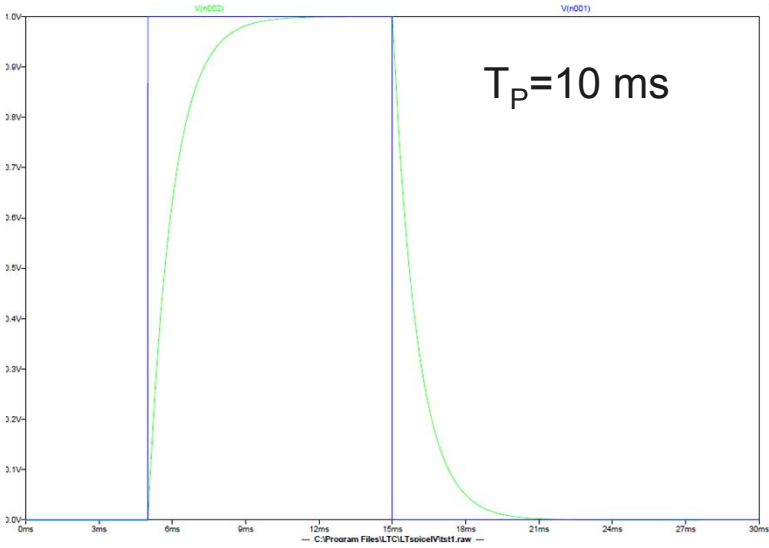
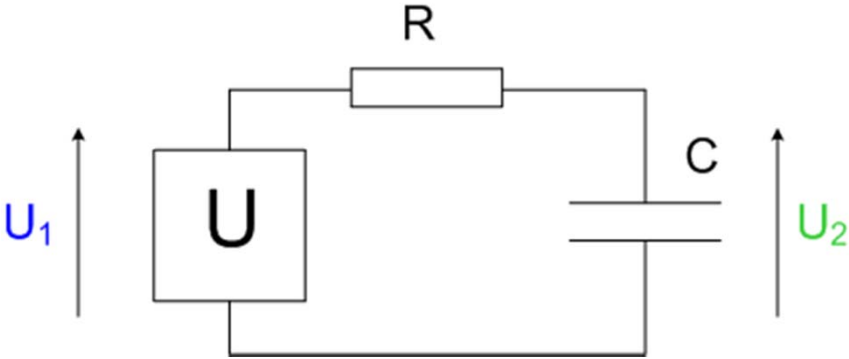
$$\rho=1 \cdot 10^{10} \text{ } \Omega\text{cm} = 1 \cdot 10^8 \text{ } \Omega\text{m} \Rightarrow \underline{T=1 \cdot 10^{-3} \text{ s}=1 \text{ ms}}$$

<u>ρ [Ωcm]</u>	<u>T [ms]</u>
$1 \cdot 10^8$	0,01
$1 \cdot 10^{10}$	1
$1 \cdot 10^{12}$	100
$1 \cdot 10^{14}$	$10^4 (=10 \text{ s})$

RC circuit, pulse response



$$\tau = R \cdot C = 1 \text{ ms}$$



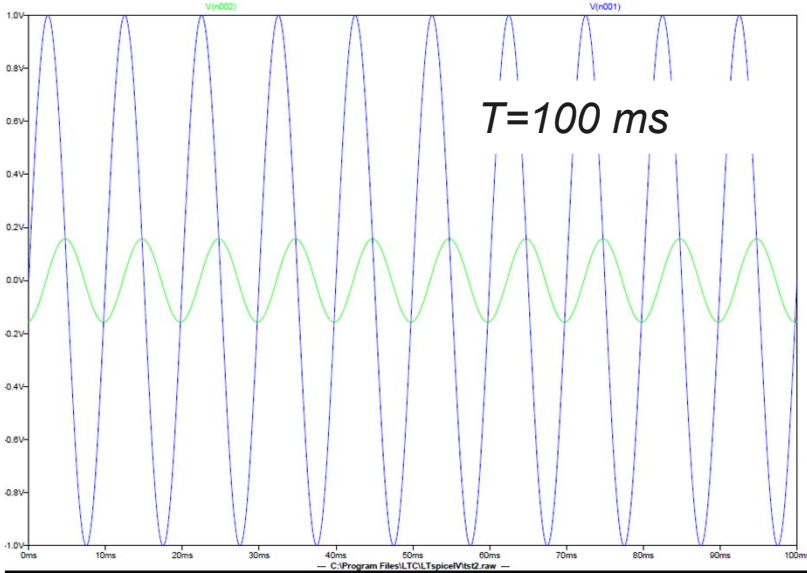
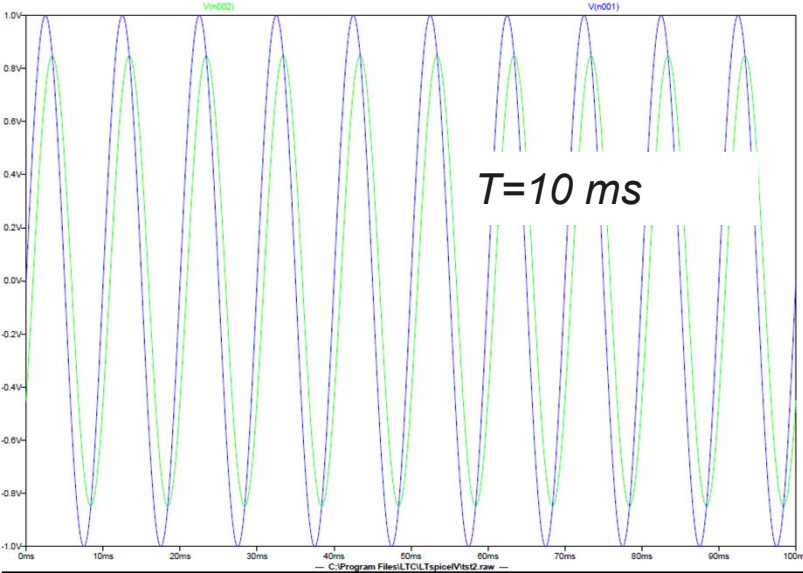
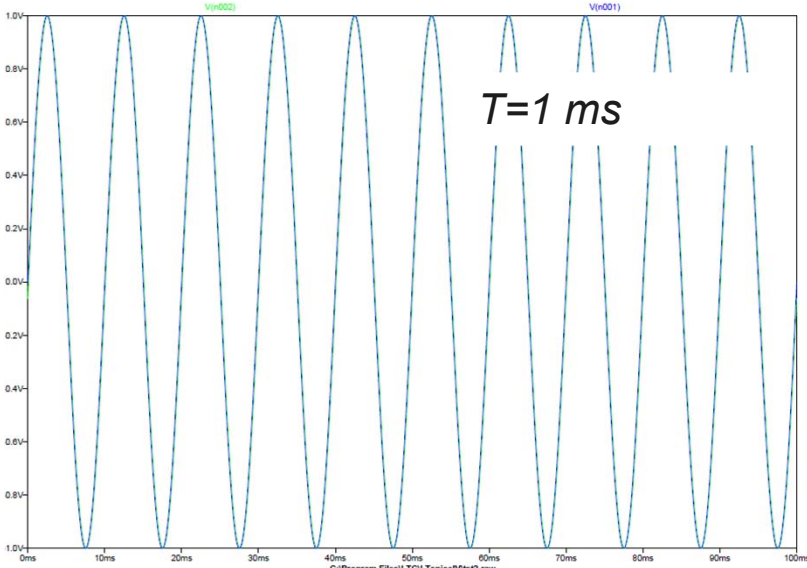
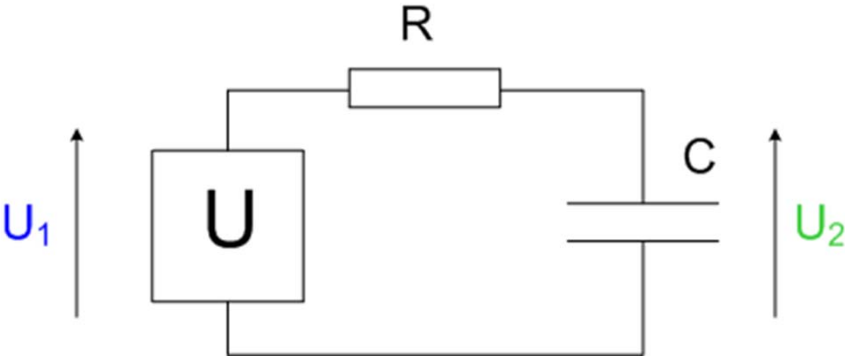
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RC circuit, frequency response

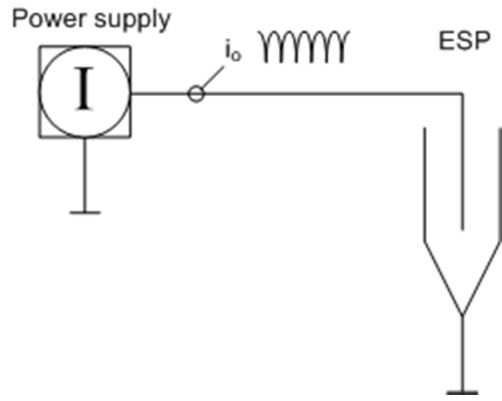


100 Hz, sine wave

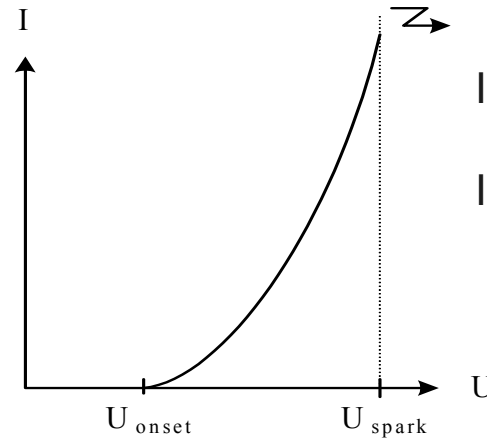
$$\tau = R \cdot C$$



Electrical system



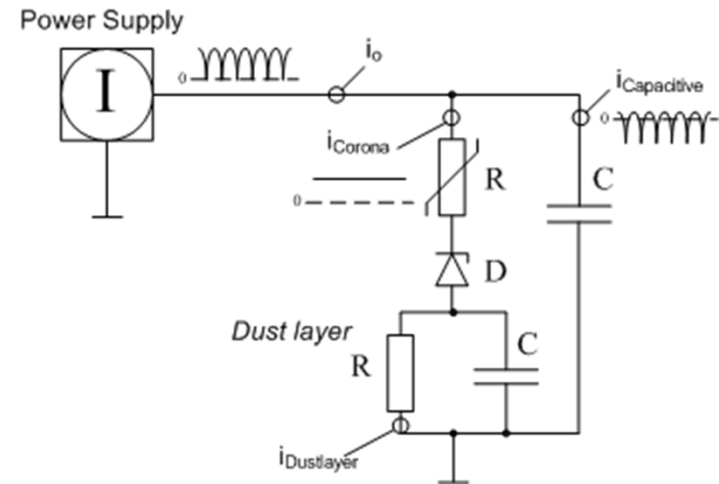
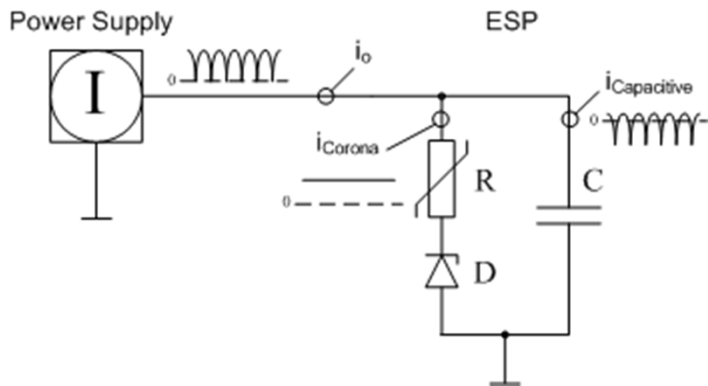
VI-curve



$$I=0, \quad U \leq U_{Onset}$$

$$I \approx k(U - U_{Onset})^2, \quad U > U_{Onset}$$

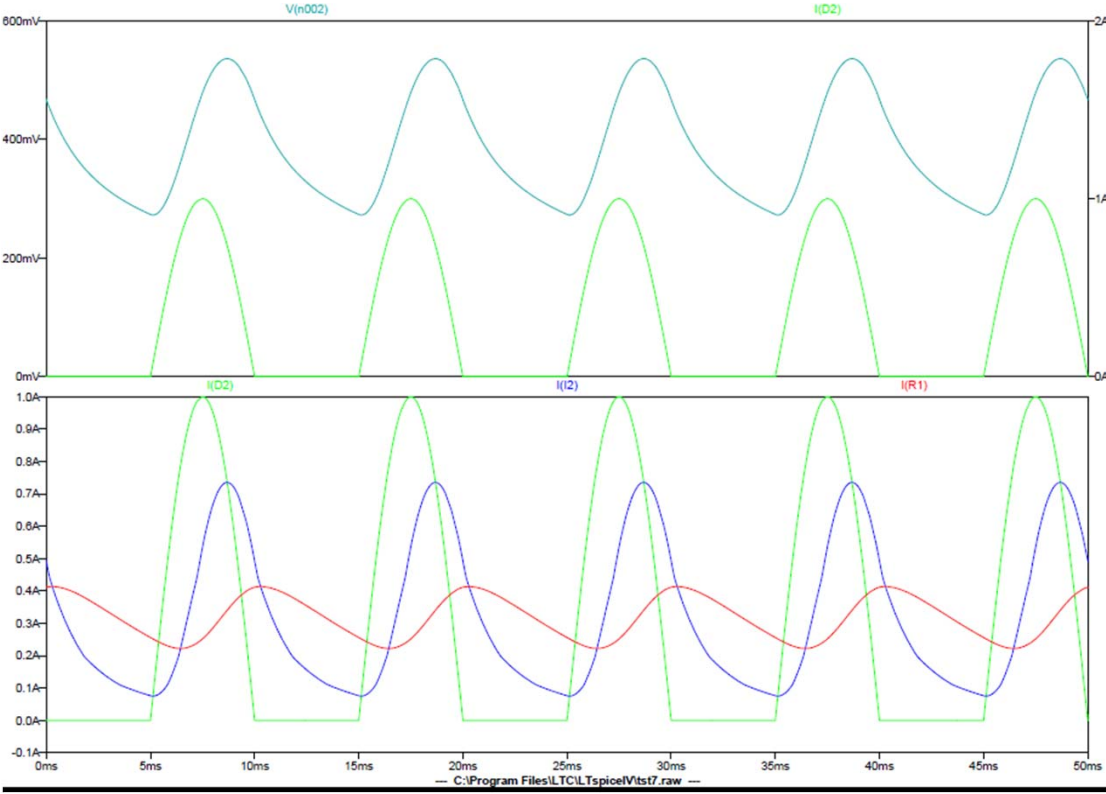
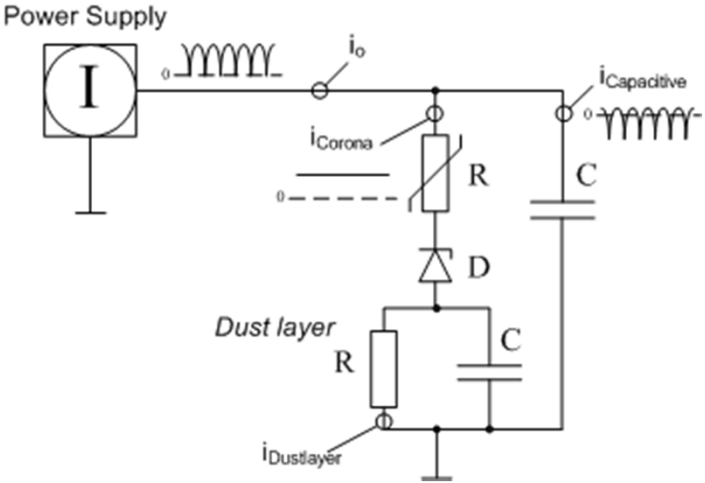
Equivalent circuit



Conventional T/R, 1:1 operation

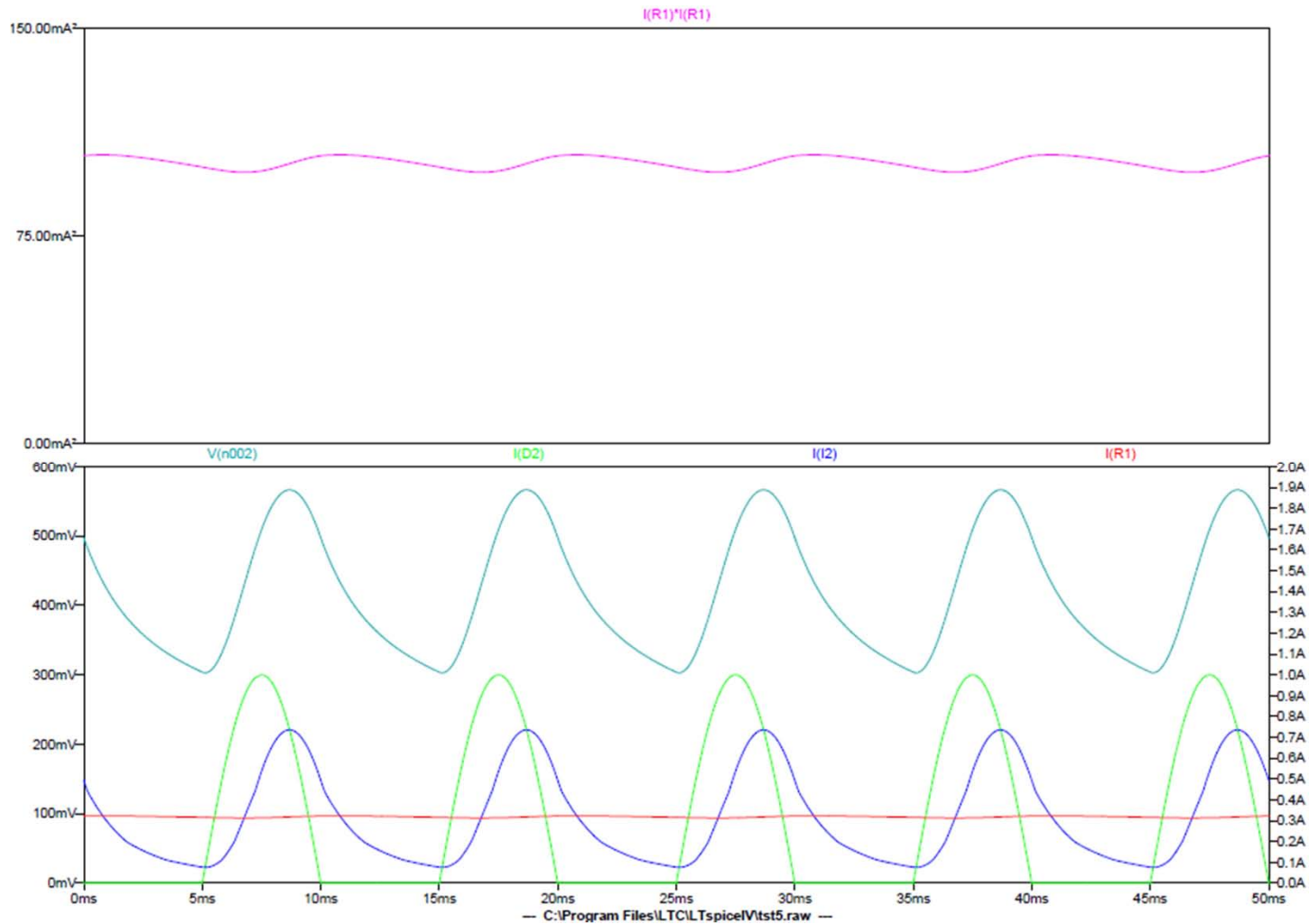


$F=2*50 \text{ Hz}$
 $\hat{I}_0=1 \text{ A}$
 $i_{\text{Corona}}(<15 \text{ kV})=0$
 $i_{\text{Corona}}(60 \text{ kV})=1 \text{ A}$



Conventional T/R, 1:1 operation

$T=100\text{ ms}$ ($10^{12}\ \Omega\text{cm}$)

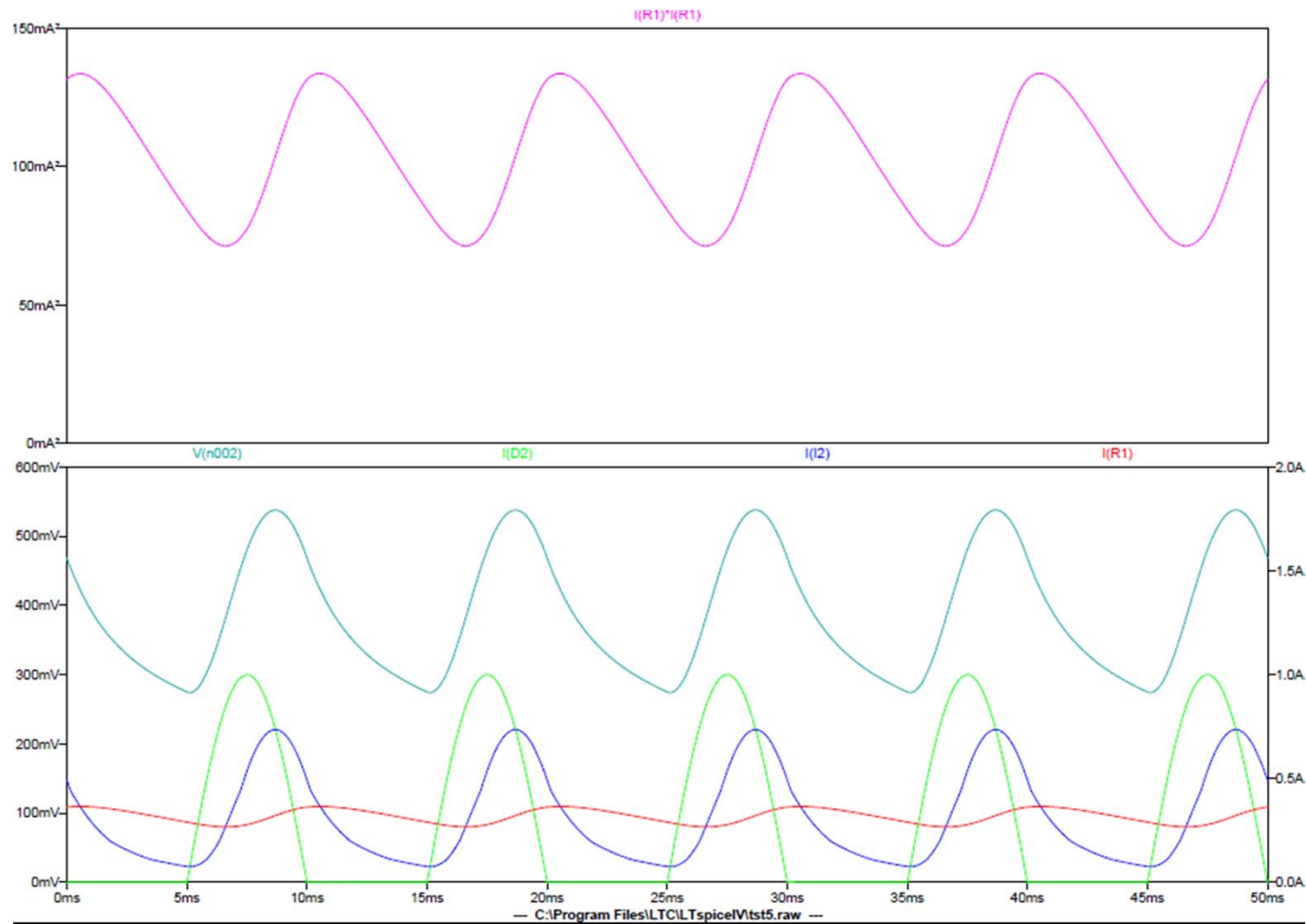


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Conventional T/R, 1:1 operation

$T=10\text{ ms}$ ($10^{11}\ \Omega\text{cm}$)

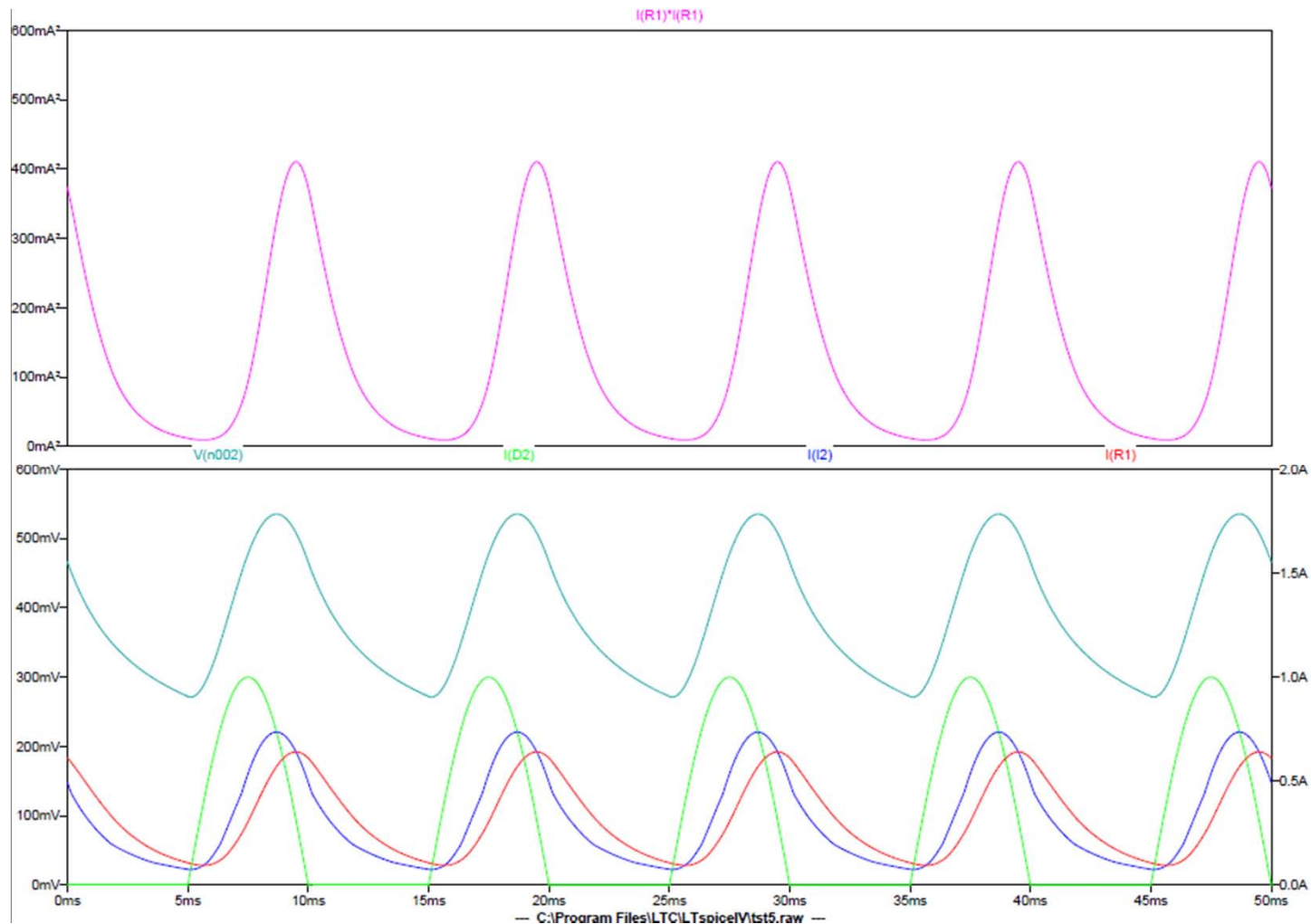


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Conventional T/R, 1:1 operation

$T=1\text{ ms}$ ($10^{10}\ \Omega\text{cm}$)

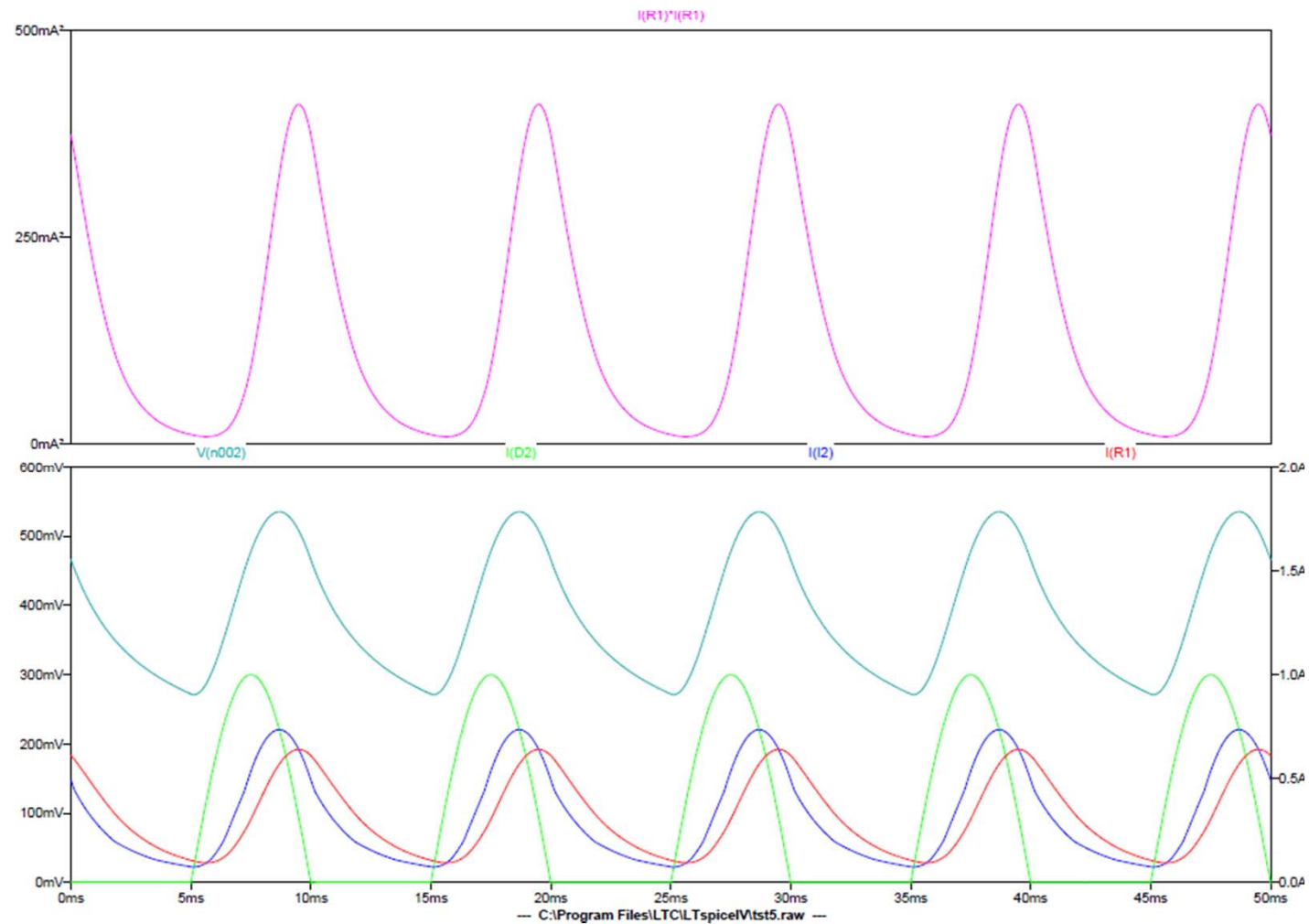


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Conventional T/R, 1:1 operation

$T=0.01 \text{ ms}$ ($10^8 \text{ } \Omega\text{cm}$)

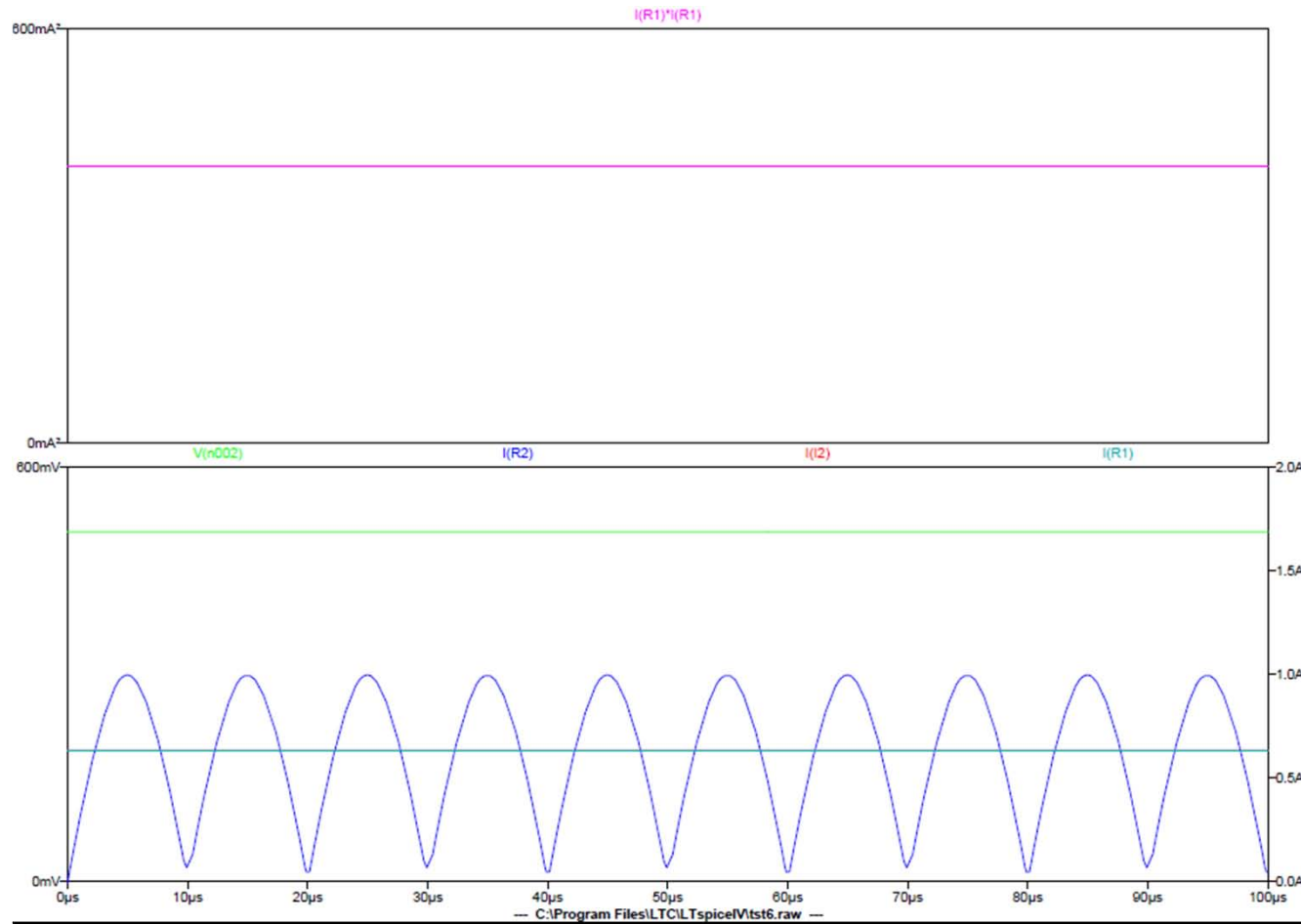


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HFPS, continuous current operation

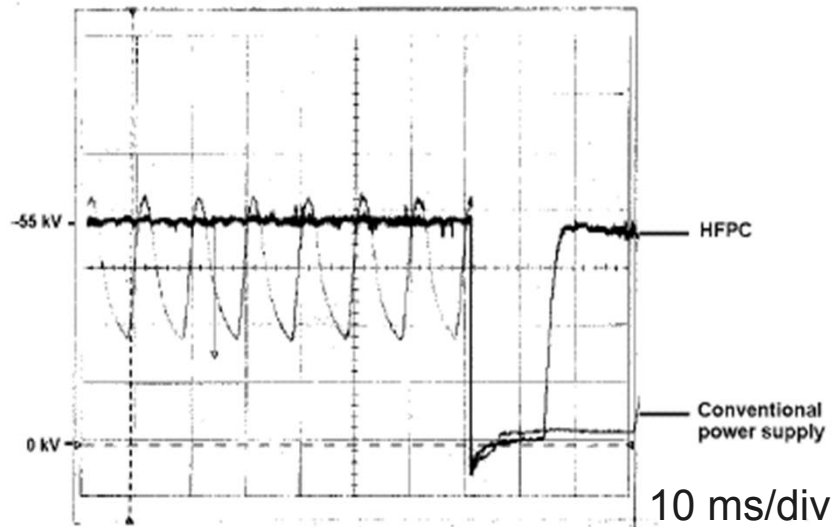
$T=0.01\text{ ms}$ ($10^8\ \Omega\text{cm}$)



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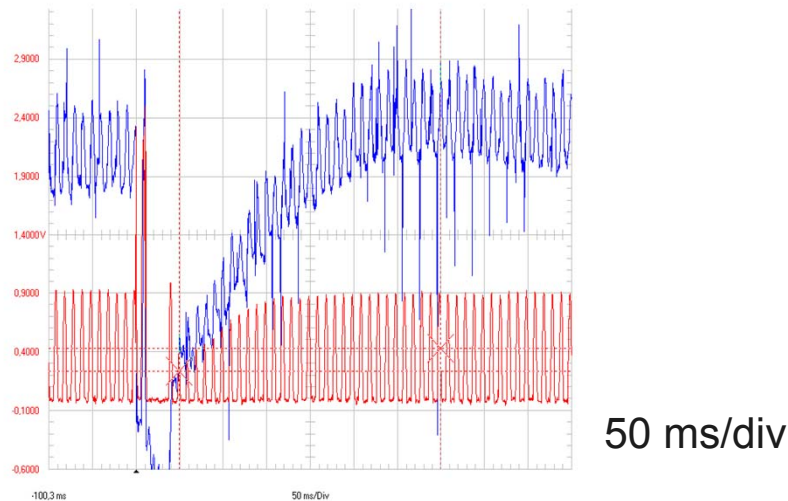
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Time variations of current, spark recovery



HFPS may have a shorter blocking time, no 50/60 Hz dependency

Superior bandwidth of the control loop (faster) enables improved spark recovery.



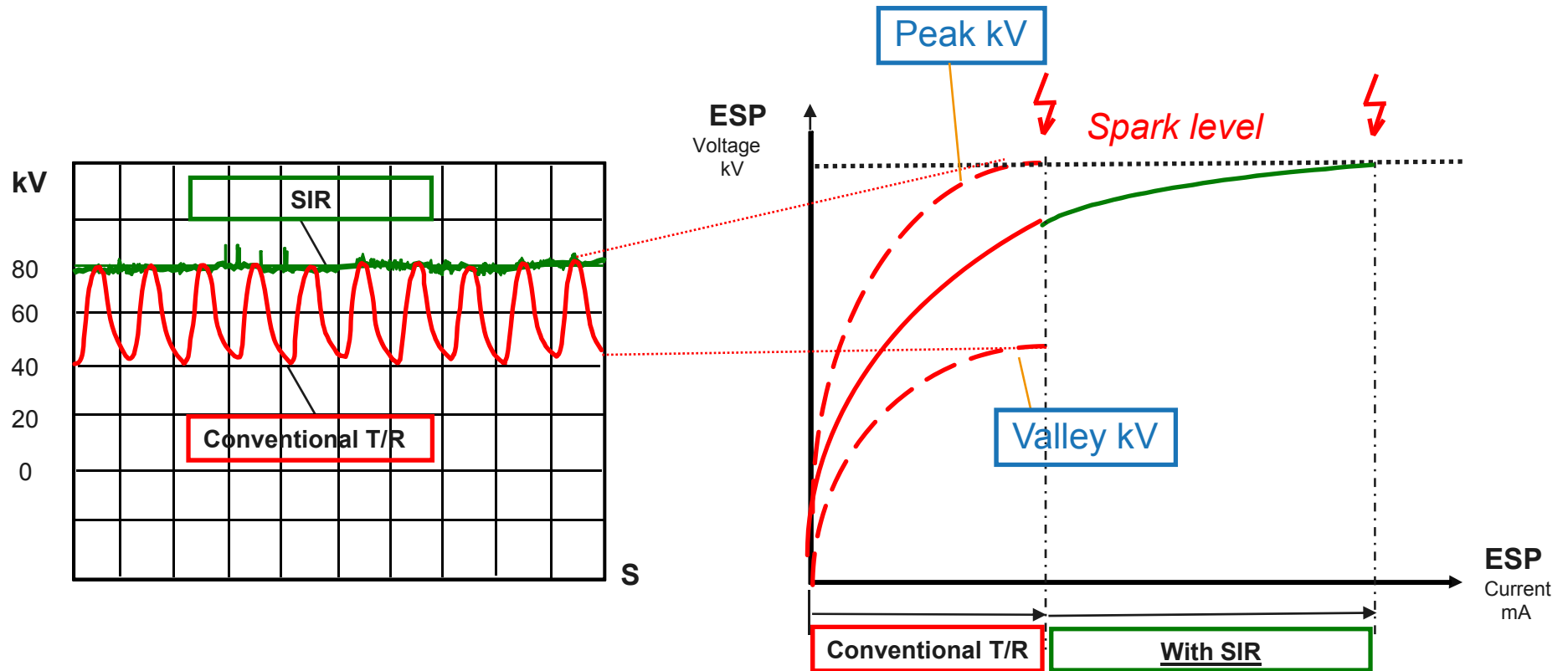
Time variations of holding forces, means to minimize reentrainment



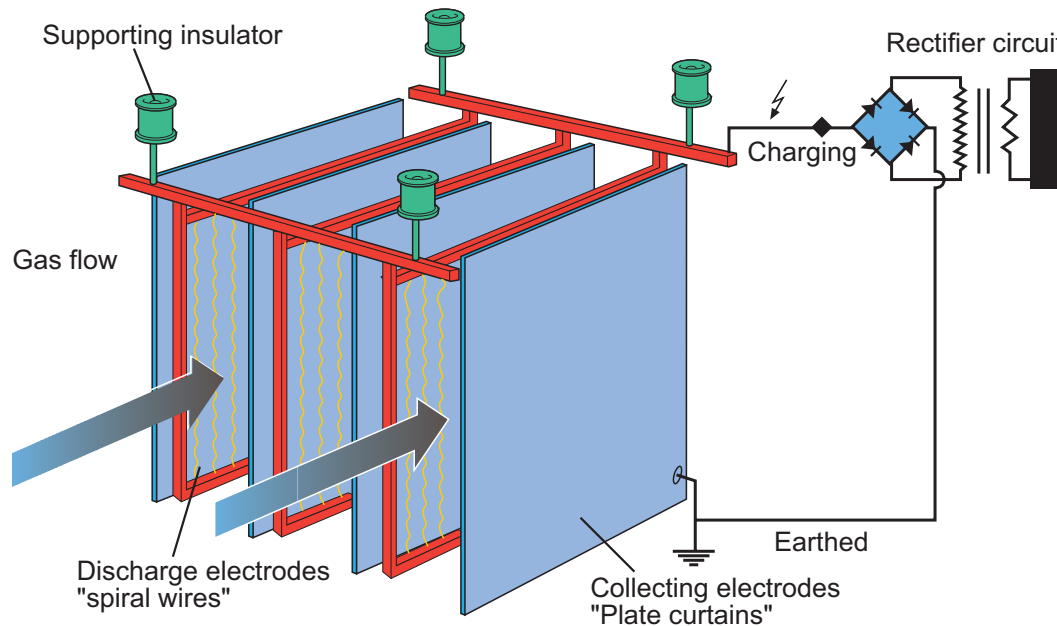
- Simulations indicate risk of reentrainment
Low and Medium resistivity
- Low Voltage ripple
- Spark over control
 - Minimize blocking time
 - Optimize voltage recover

- *Introduction*
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HFPS vs. Conventional T/R Electrical Performance – Output Voltage



Test system set-up, Air load



Collecting Area:
 $A = 50 \text{ m}^2$

Electrode spacing:
 $D = 400 \text{ mm}$

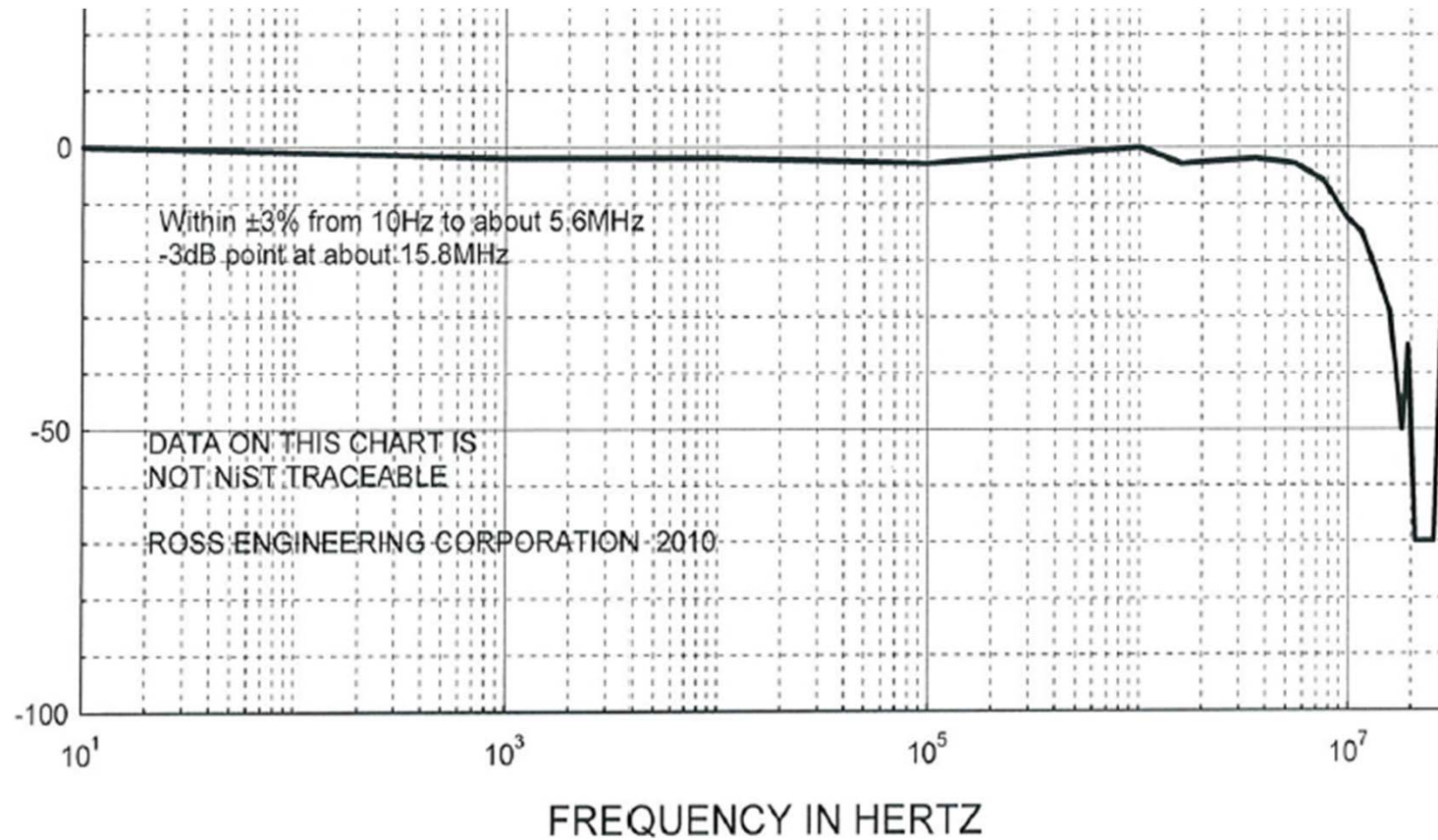
Discharge electrode:
Spiral (30/2,7)

Power Supply:
T/R set (ADOR)
HFPS (SIR)

External voltage sensor:
Wide Bandwidth Volt.Div.
15 MHz (Ross Eng.)

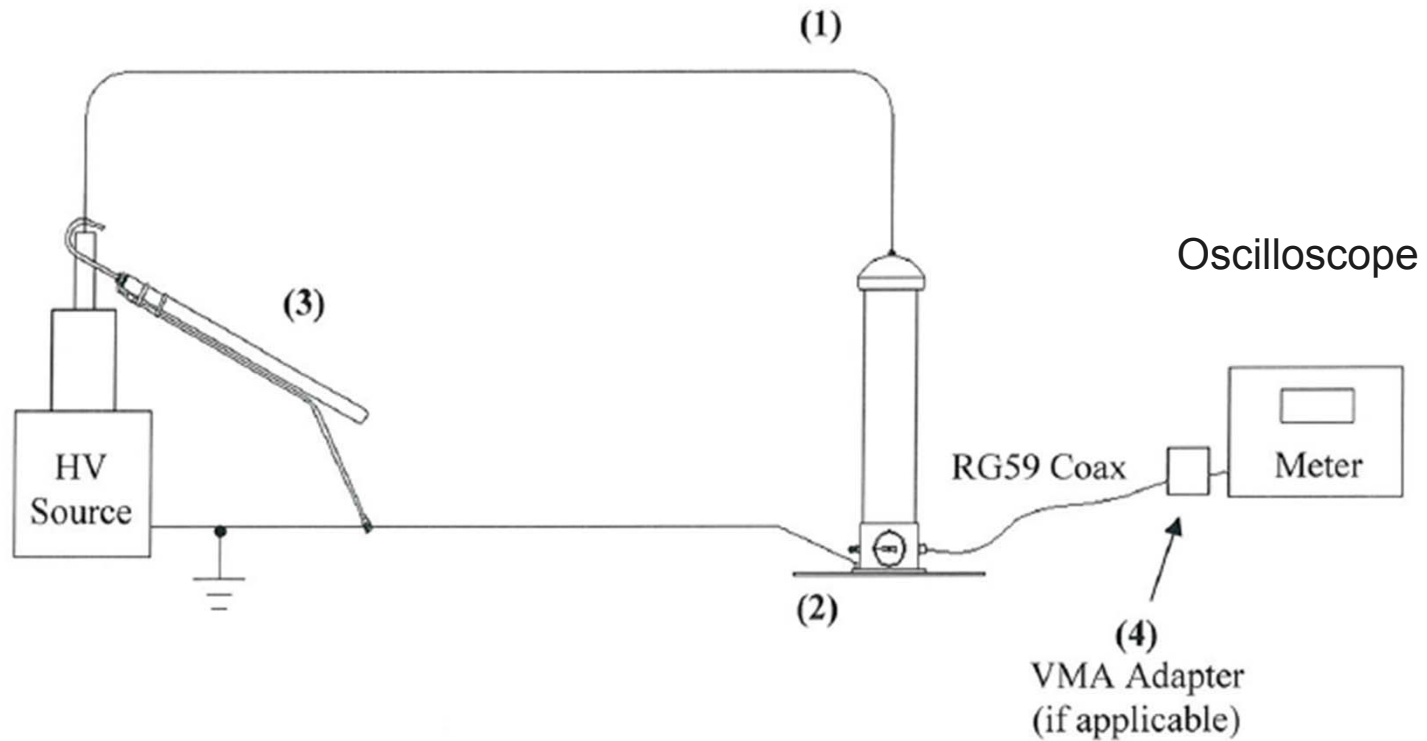
Oscilloscope:
Tektronix, DSO
500 MHz, 4 ch

HFPS vs. Conventional T/R Comparison – Output Voltage



(Extract from manual)

External sensor, set-up

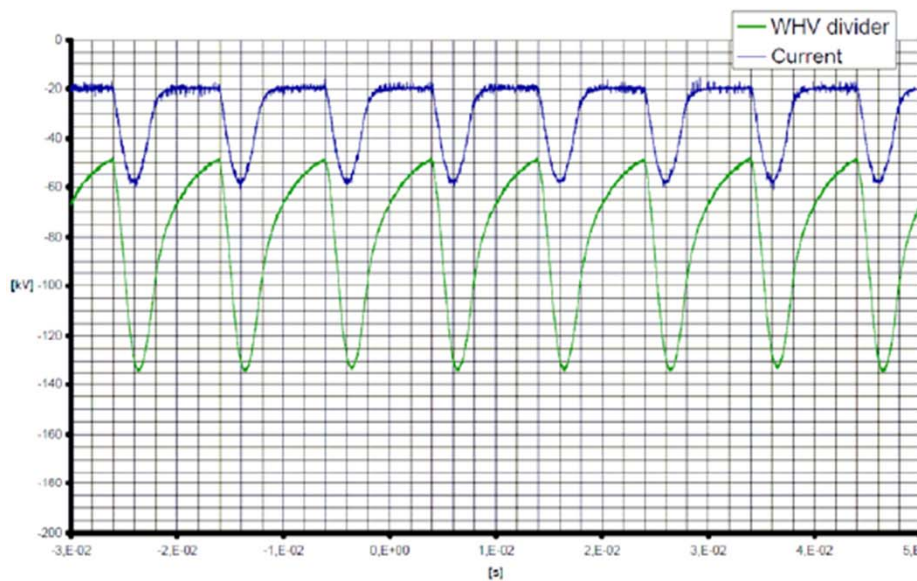


(Extract from manual)

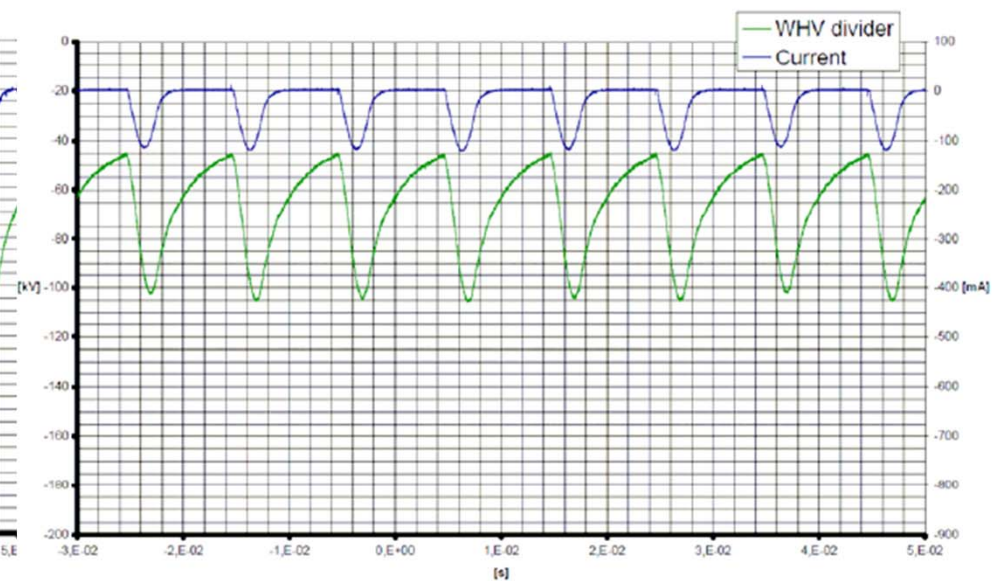
Conventional T/R, 1:1 operation $I=50\text{ mA}$, 25 mA , external sensors



50 mA (1 mA/m^2)



25 mA ($0,5\text{mA/m}^2$)



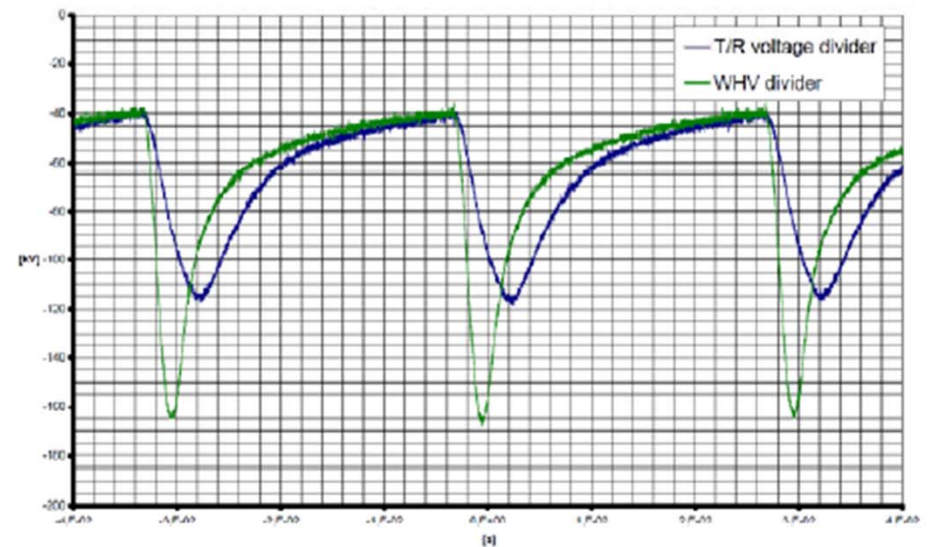
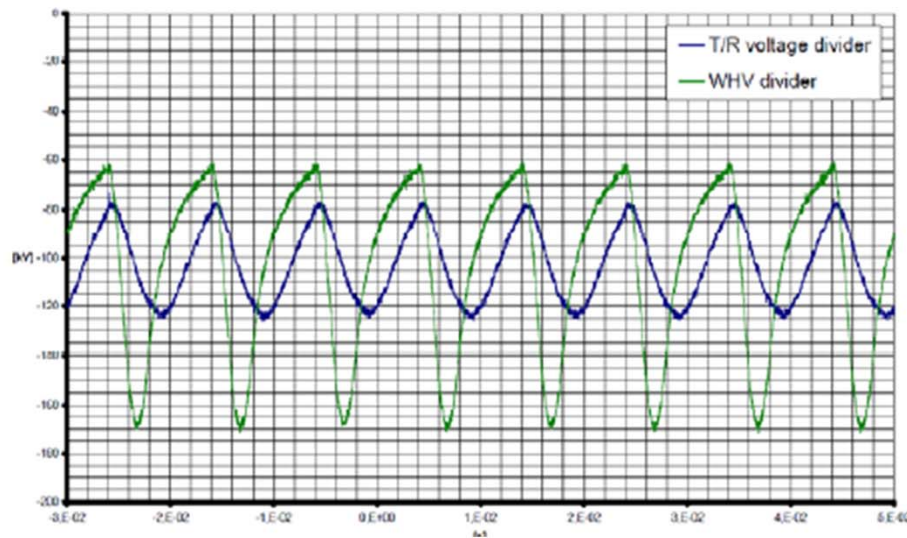
20 kV/div, 100 mA/div,
10 ms/div

Conventional T/R, 1:1, 1:3 T/R signal vs External sensor



1:1

1:3



20 kV/div, 10 ms/div

HFPS vs. Conventional T/R Same peak voltage

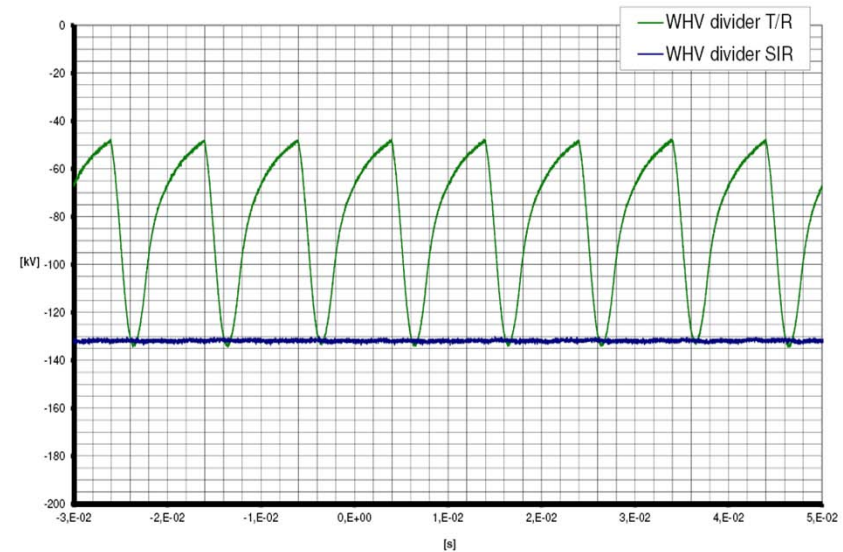
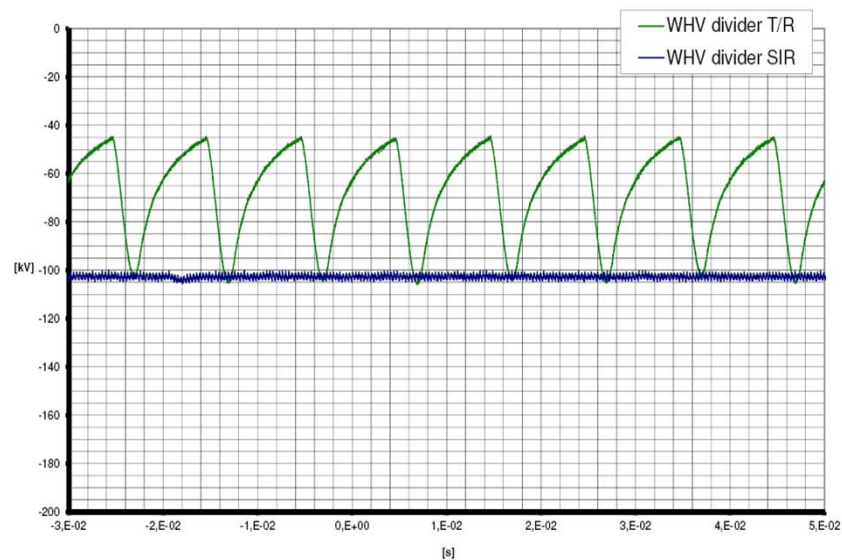


Conventional T/R: 25 mA

HFPS: 75 mA

Conventional T/R: 50 mA

HFPS: 150 mA



20 kV/div, 10 ms/div

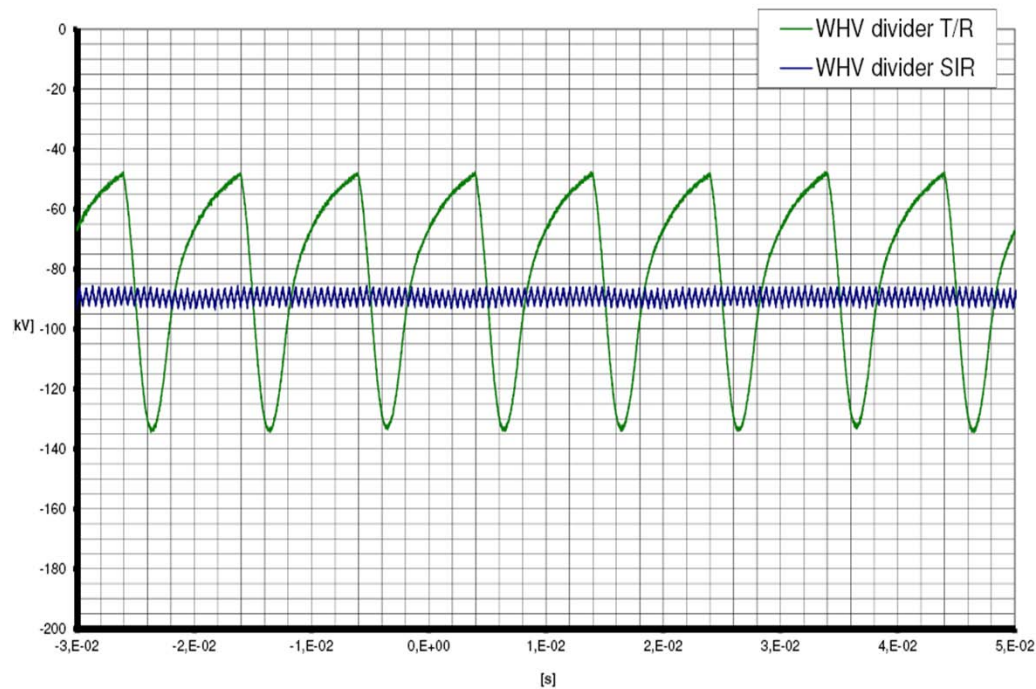
HFPS vs. Conventional T/R

Same current (average), 50 mA



Conventional T/R: 80 kV_{AVG}

HFPS: 90 kV_{AVG}

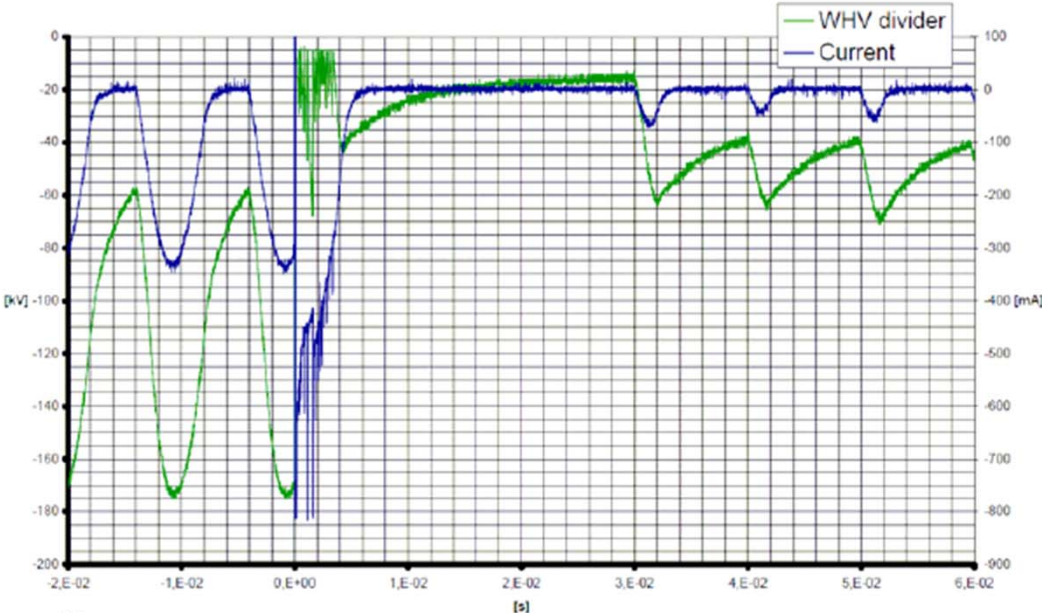


20 kV/div, 10 ms/div

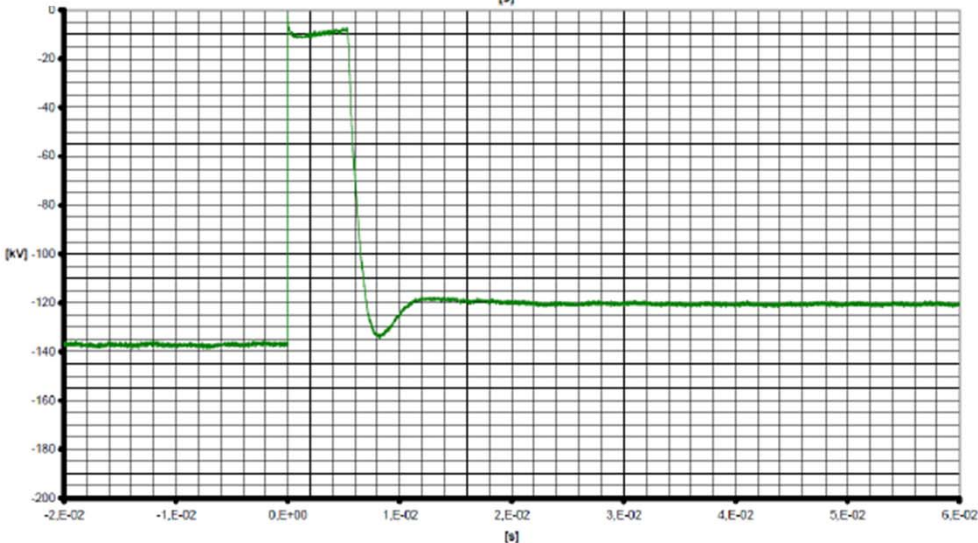
HFPS vs. Conventional T/R Comparison – Spark recovery



Conventional T/R



HFPS



20 kV/div, 10 ms/div

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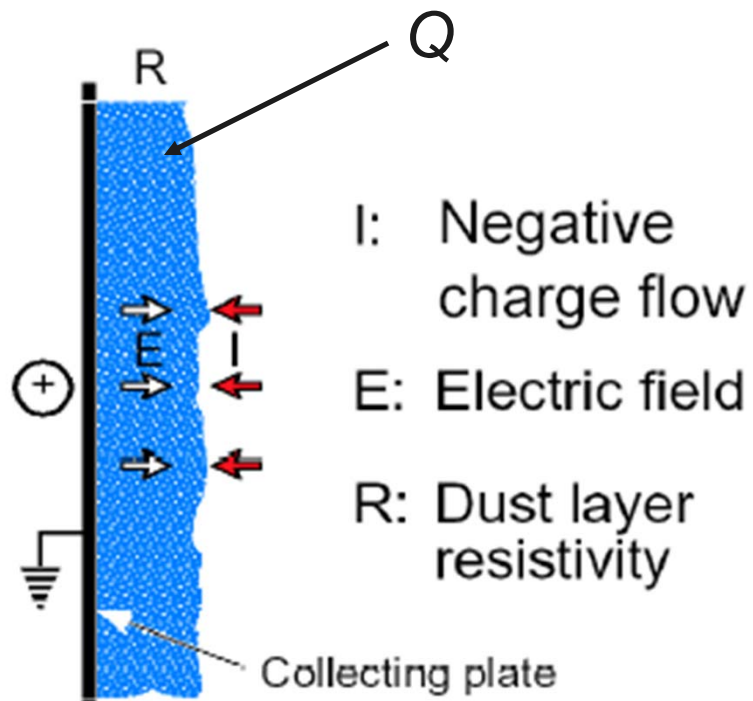
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- For precise measurement use
Wide Bandwidth Voltage Dividers

- Peak voltage may be higher than expected

- *Introduction*
- *Holding forces, variations in time*
- *High voltage measurements*
- ***Resistivity control by means of
Power Control Rapping***
- *Summary*

Dust layer, electrostatics



$$F = Q E$$

$$E = j \rho$$

$$\Rightarrow F = Q j \rho$$

F Force, [N]

Q Charge, [C, (As)]

E Field strength, [V/m]

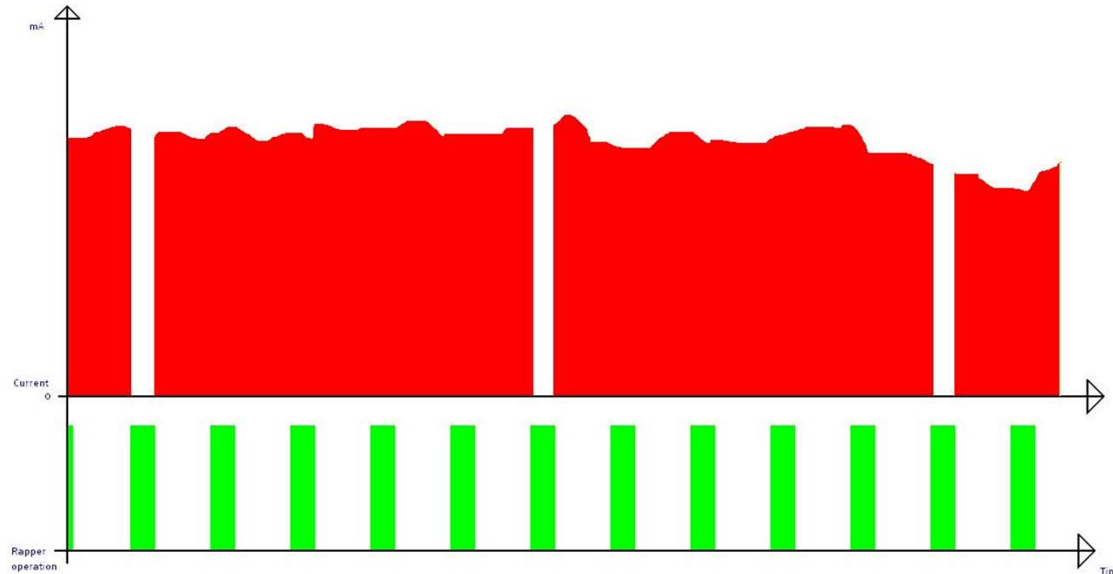
j Current density, [A/m²]

ρ Dust layer resistivity, [Ω m]

Power Control Rapping

- Reduces electrical holding forces
- Important at back-corona situations where accumulation of high resistivity dust over time increases the dust difficulty
- Normally PCR is not necessary every cycle. Often every 5 (difficult) or less frequent is enough
- Preferably do exit field PCR at night when ambient temperature impact is low and boiler load is low
- If the control system is upgraded for more power, the need for PCR will be more likely, i.e. SIR.

Power Control Rapping

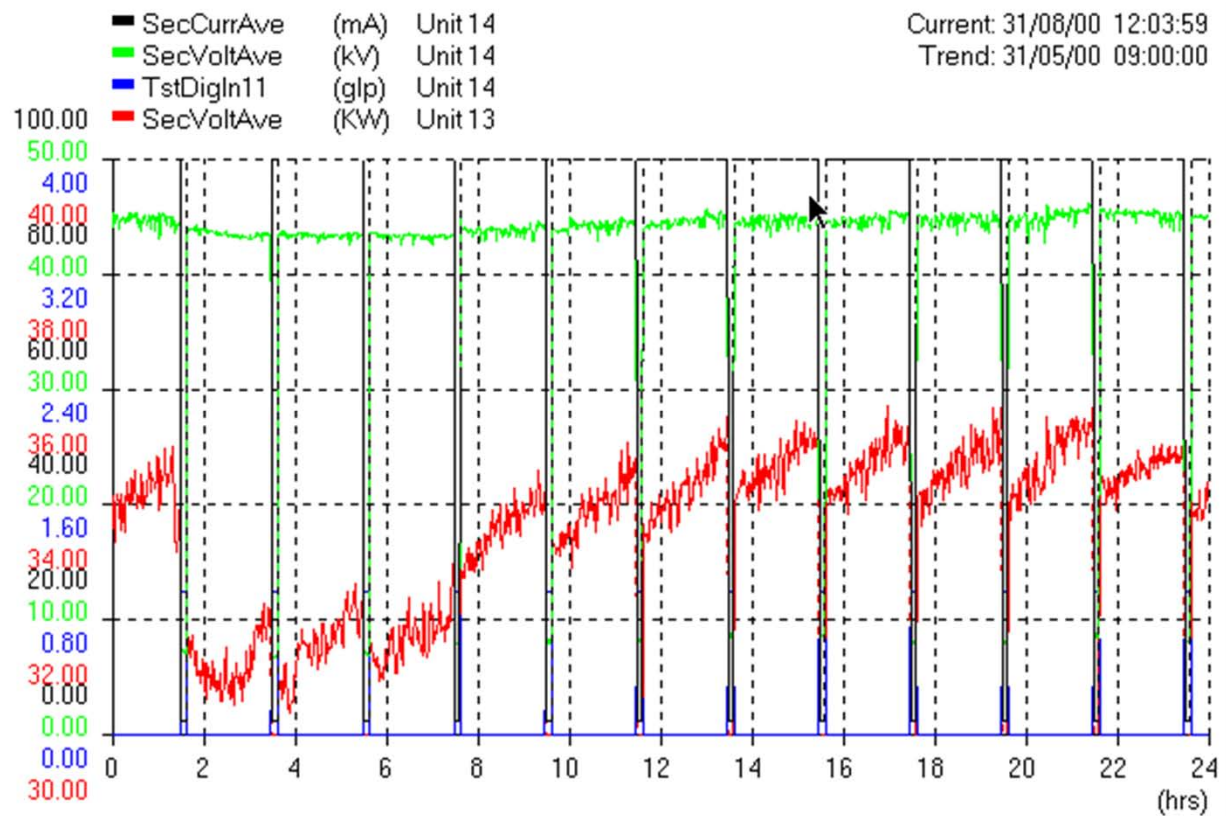


- Red is secondary current. Green is rapper operation. mA drop is PCR

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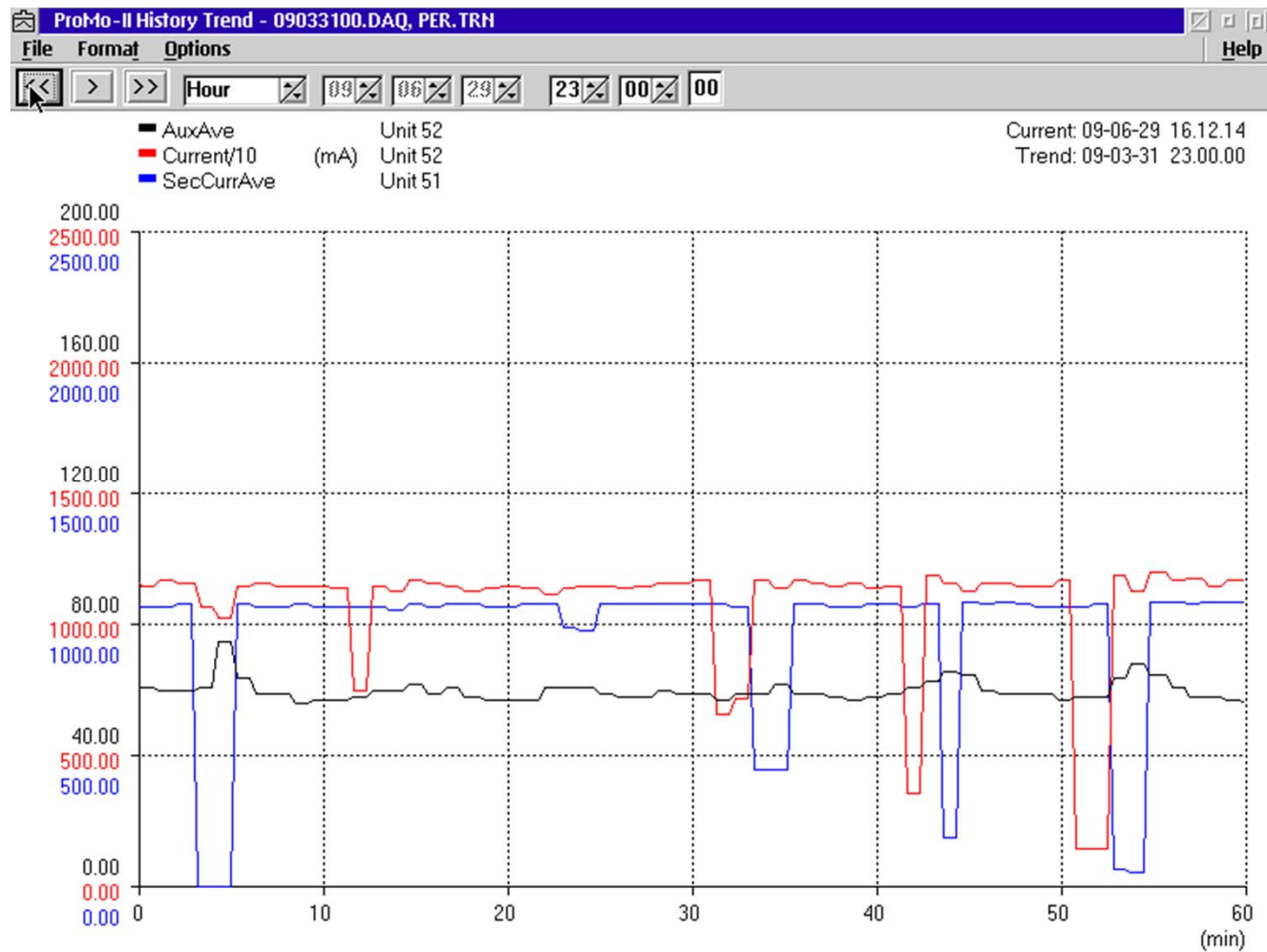
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Tuning Rappers-PCR



- Note the drop in kV after PCR every two hours. This is a second field and this drop is a good
- Sign of working Power Control Rapping

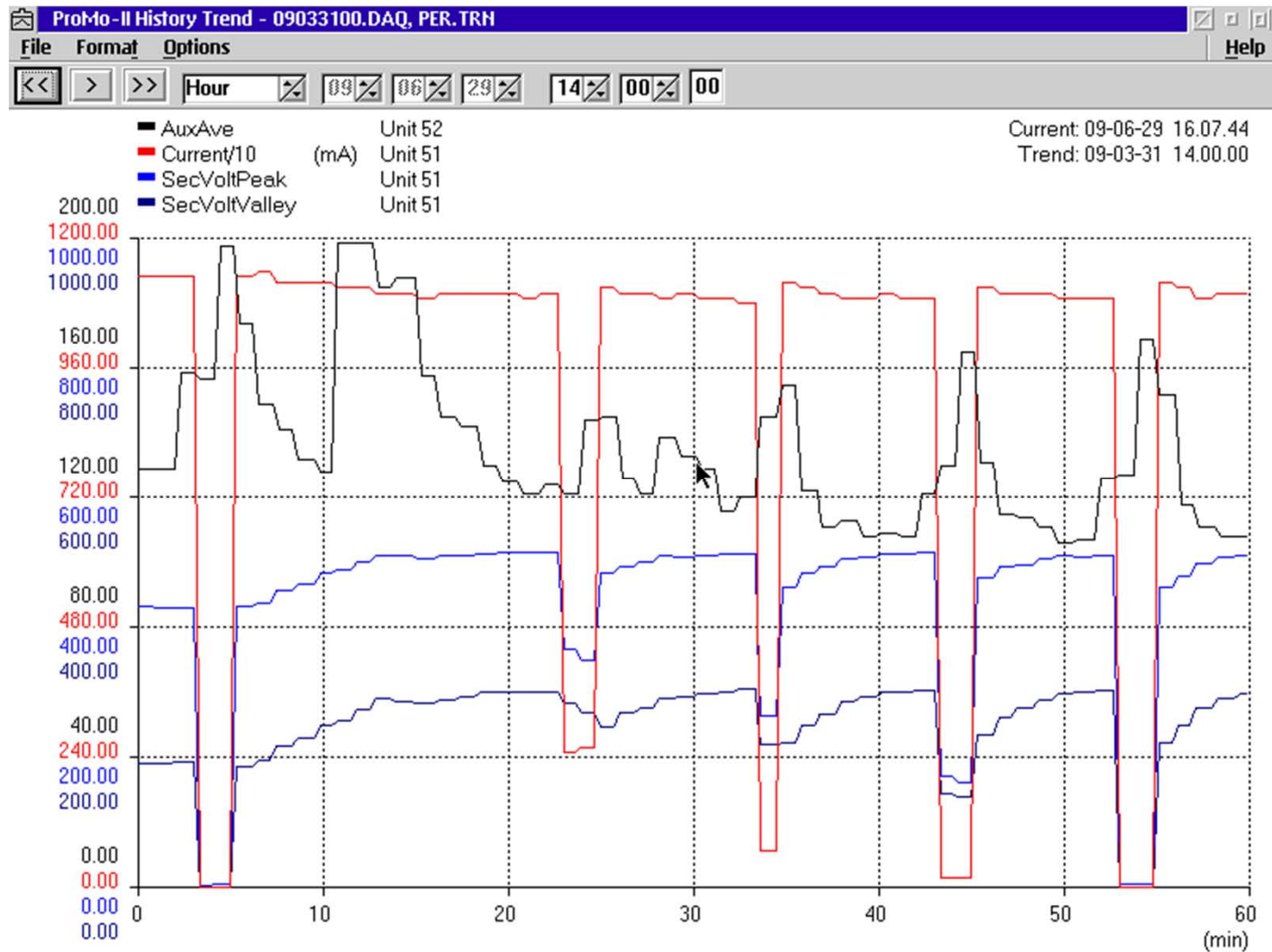
PCR Rapping sequence



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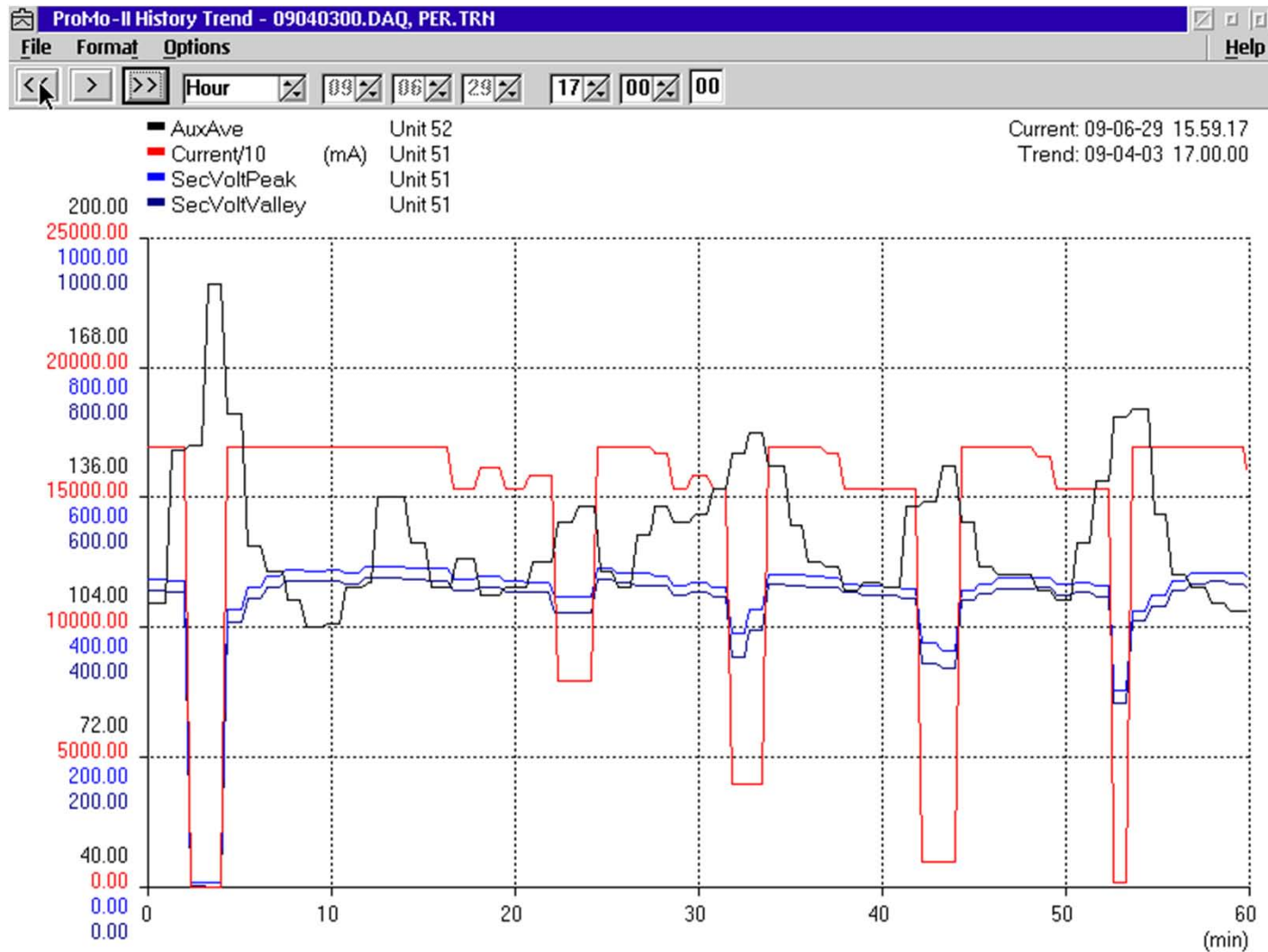
PCR Rapping sequence



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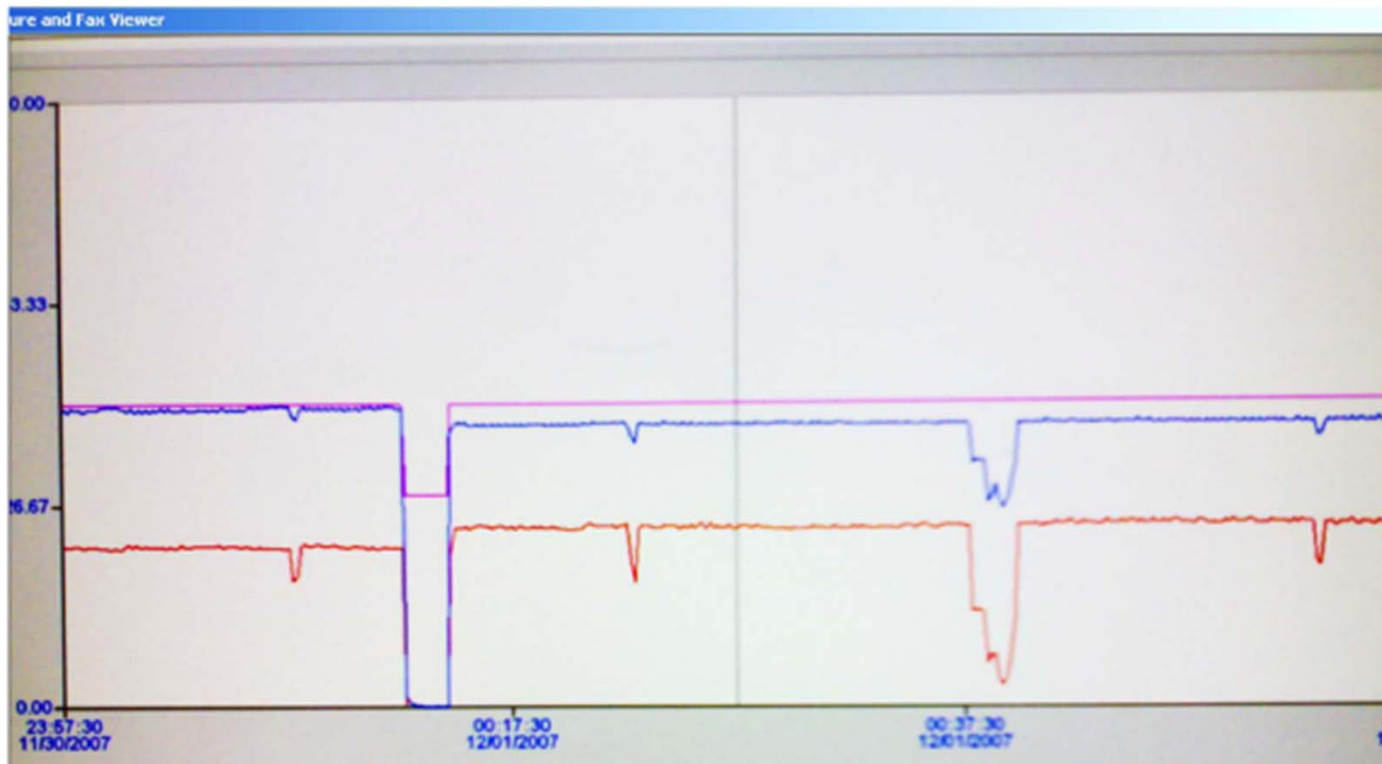
PCR Rapping sequence



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PCR with EPOQ optimization



Secondary voltage

Secondary current

- *Introduction*
- *Holding forces, variations in time*
- *High voltage measurements*
- *Resistivity control by means of*
Power Control Rapping
- ***Summary***

- Low resistivity calls for higher current, $F=Q \cdot j \cdot \rho$
- Time variation of Corona current
Risk of reentrainment for
Low and Medium resistivity ash
- Use external voltage sensors for
precise measurements
- Back Corona is influenced by rapping sequence
Improved operation at high resistivity with PCR

Thanks for your attention !

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